

# ATLAS activity in KU

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Shohei Shirabe  
Kyushu University

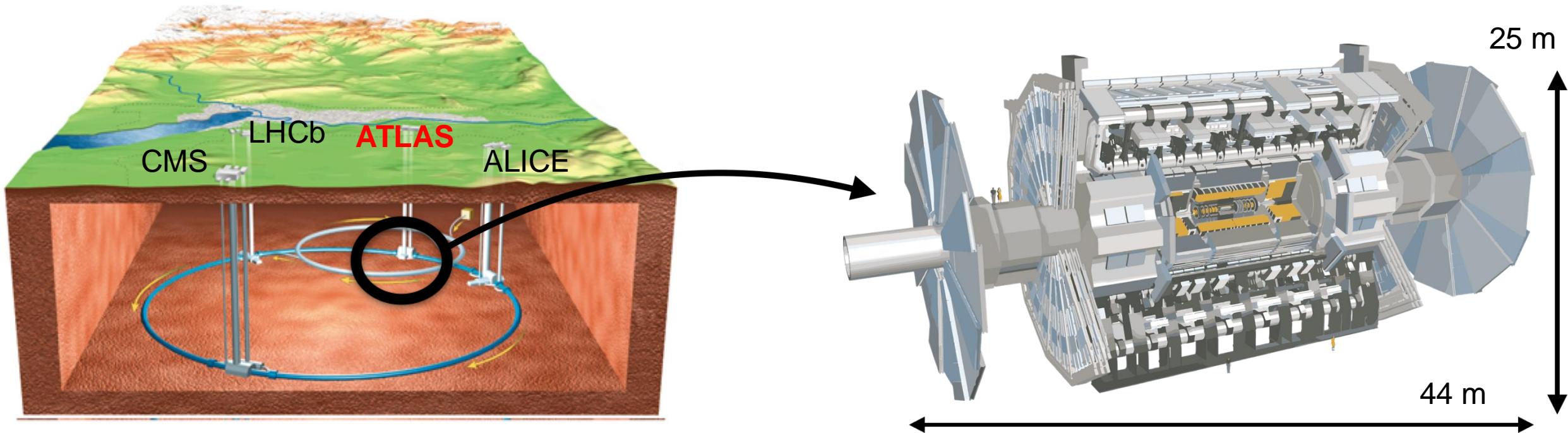
21.02.2024

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# LHC and ATLAS

## LHC

- Run3 (2022 - 2026)
- $\langle \mu \rangle \sim 60$
- $2.3 \times 10^{34} \text{ cm}^{-2}\text{s}^{-1}$
- $300 \text{ fb}^{-1}$  (183  $\text{fb}^{-1}$  so far)



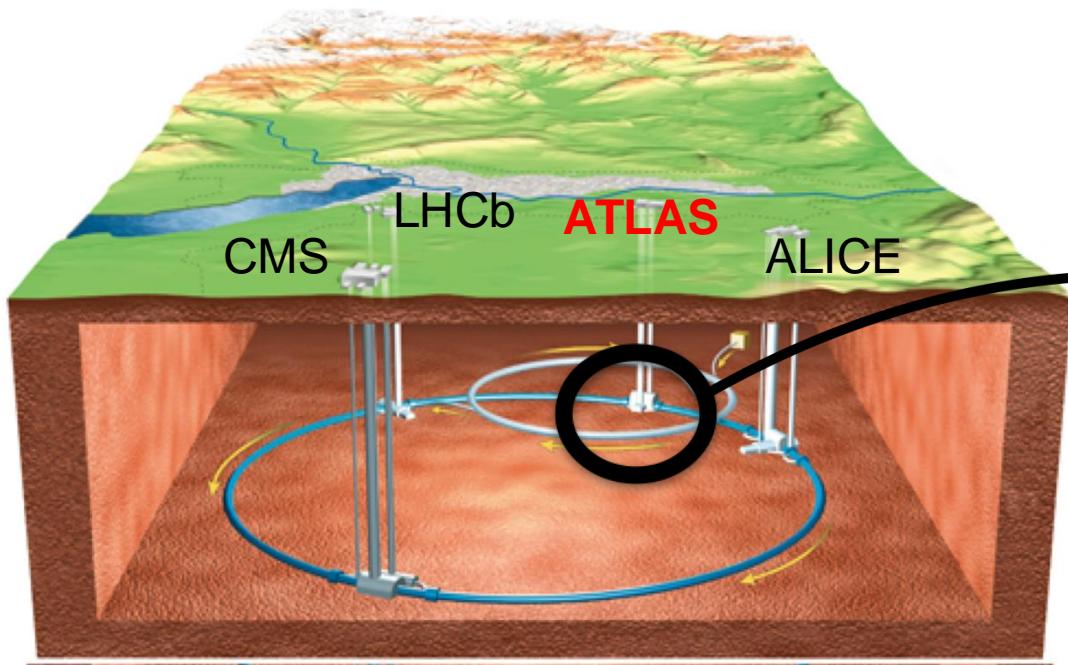
# LHC and ATLAS



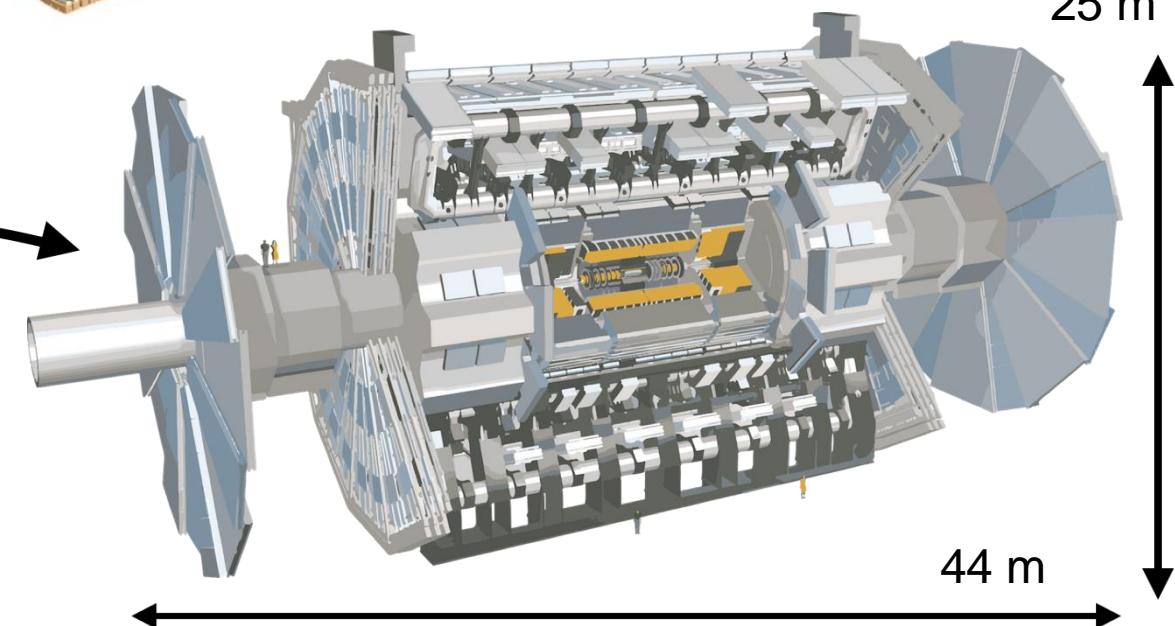
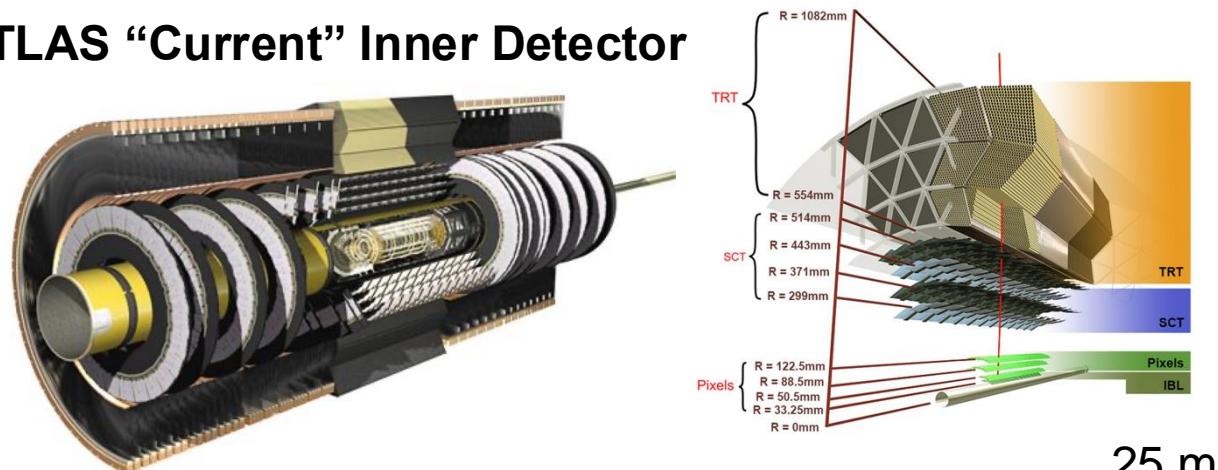
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## ATLAS “Current” Inner Detector



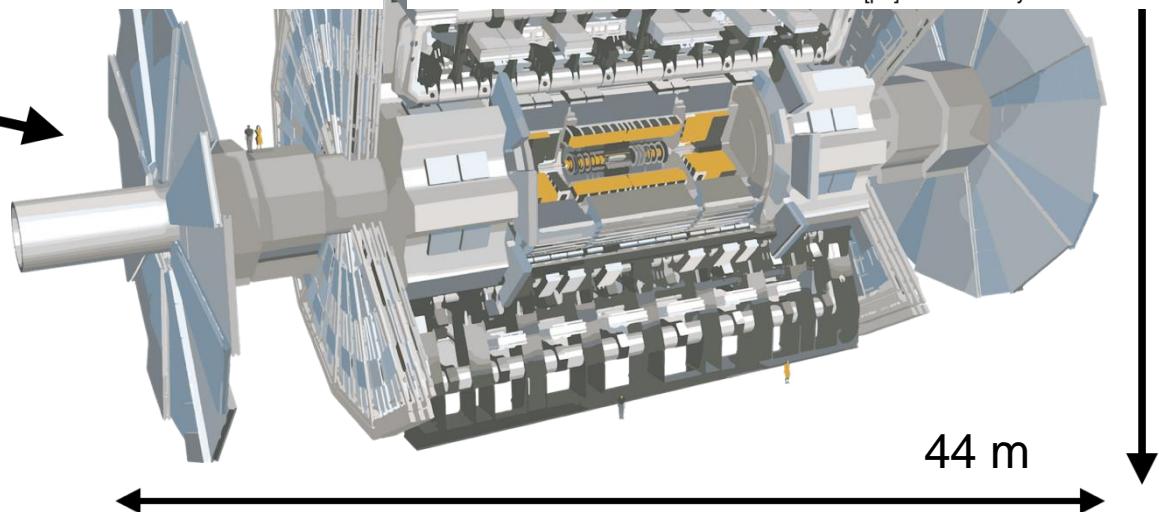
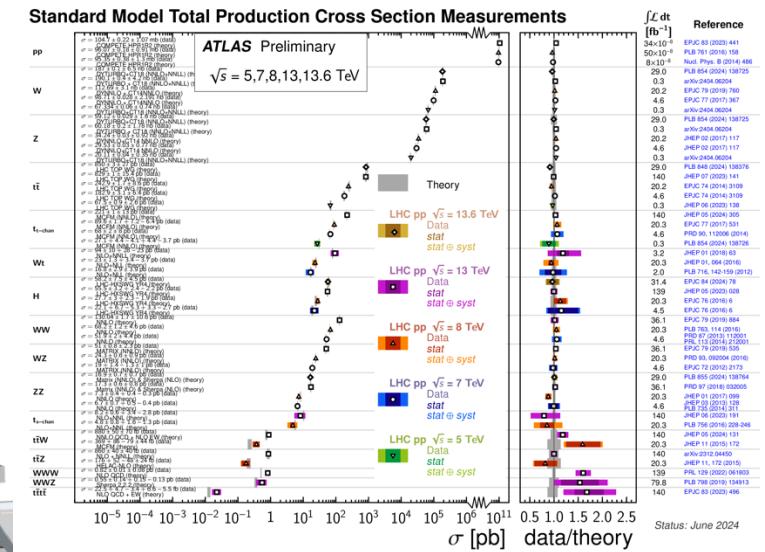
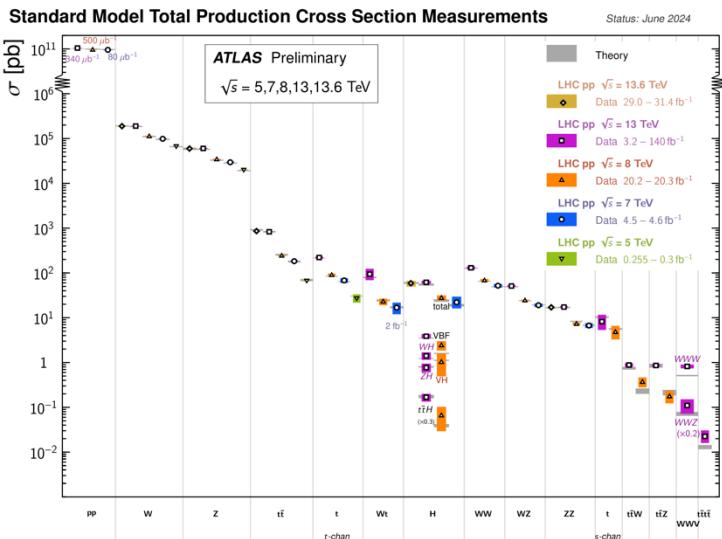
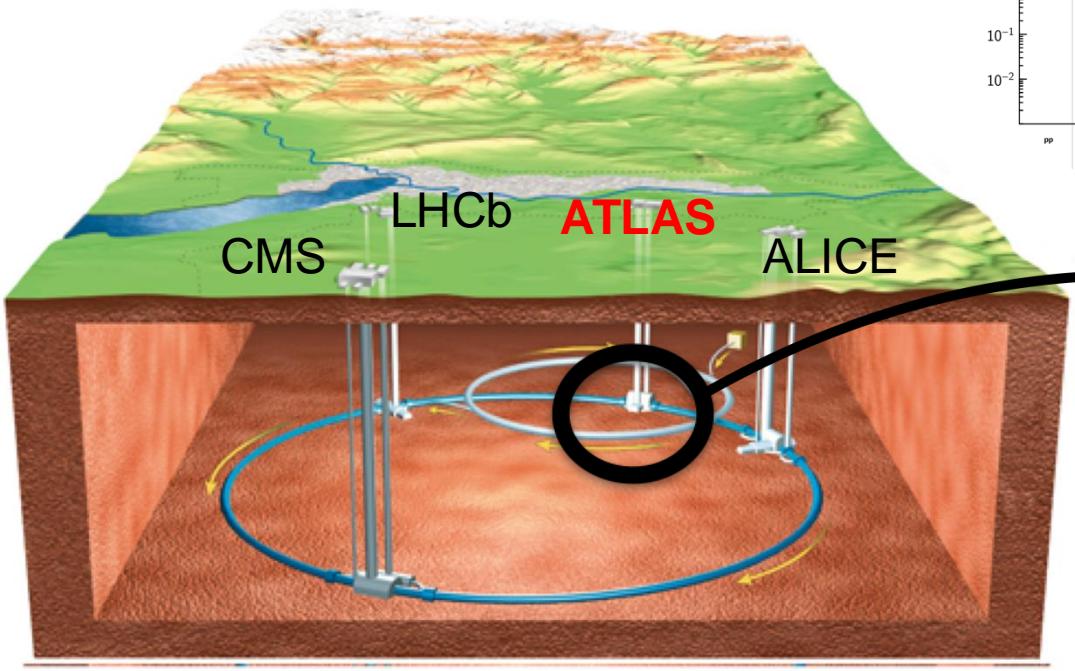
# LHC and ATLAS



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# HL-LHC Upgrade



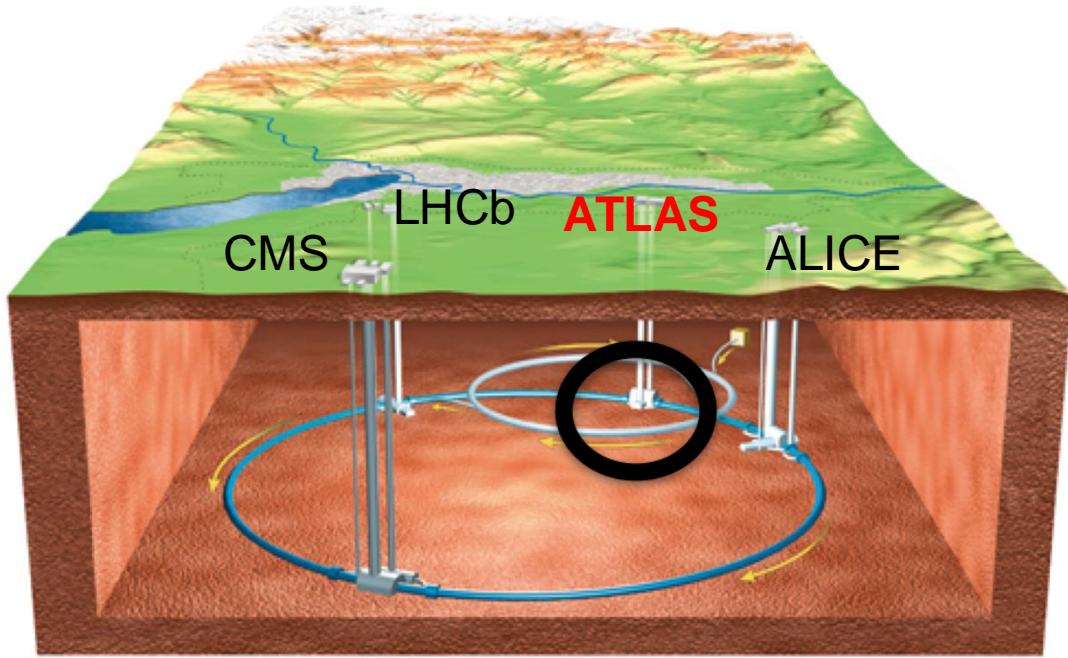
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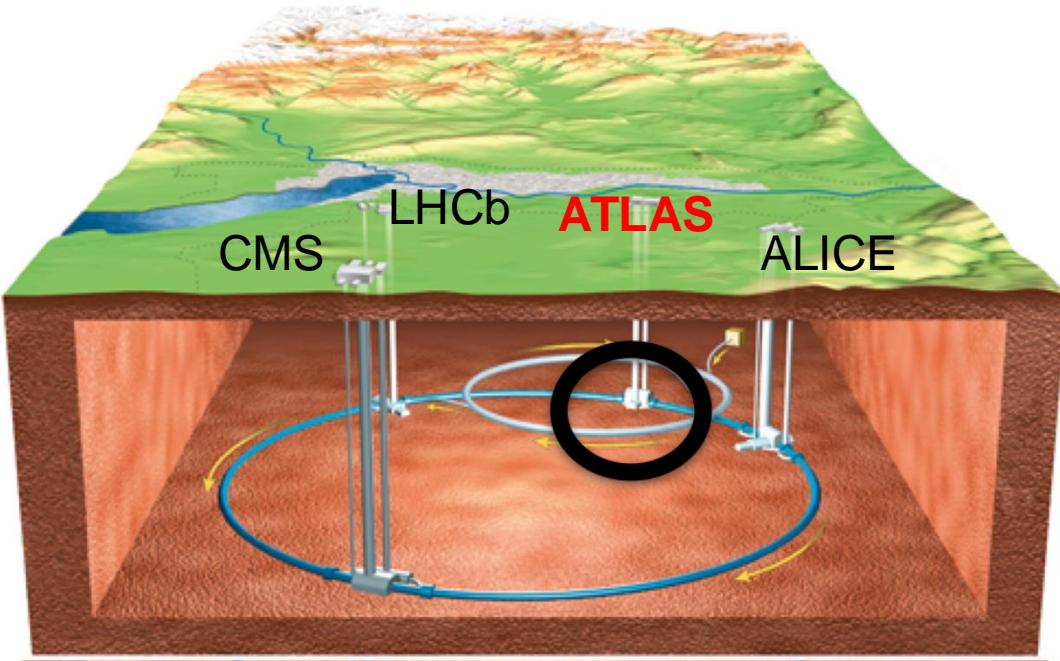
- 2030 -
- $\langle\mu\rangle \sim 60$
- $5.0 (7.5) \times 10^{34} \text{ cm}^{-2}\text{s}^{-1}$
- $3000 \text{ fb}^{-1}$  ( $183 \text{ fb}^{-1}$  so far)



# Physics Motivation

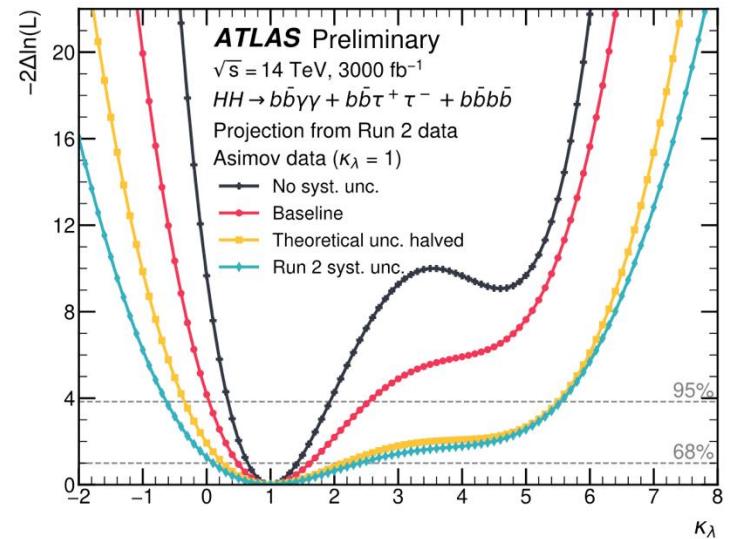
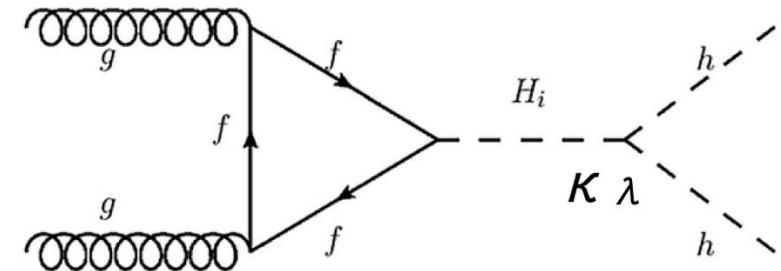
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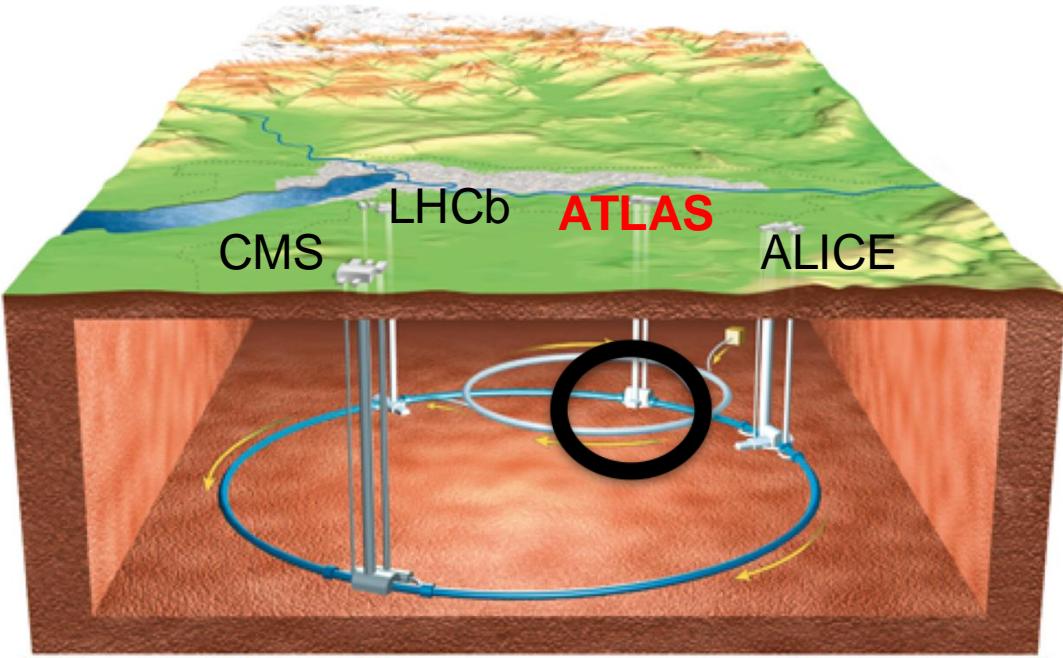
# ITk Upgrade

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Requirement for the pixel detector and its readout becomes demanding

- **Radiation tolerance**
  - Current ID Pixel designed for  $\sim 400 \text{ fb}^{-1}$
- **Bandwidth saturation**
  - Current ID designed to accommodate  $\langle\mu\rangle \sim 50$  at  $2 \times 10^{34} \text{ cm}^{-2} \text{ s}^{-1}$

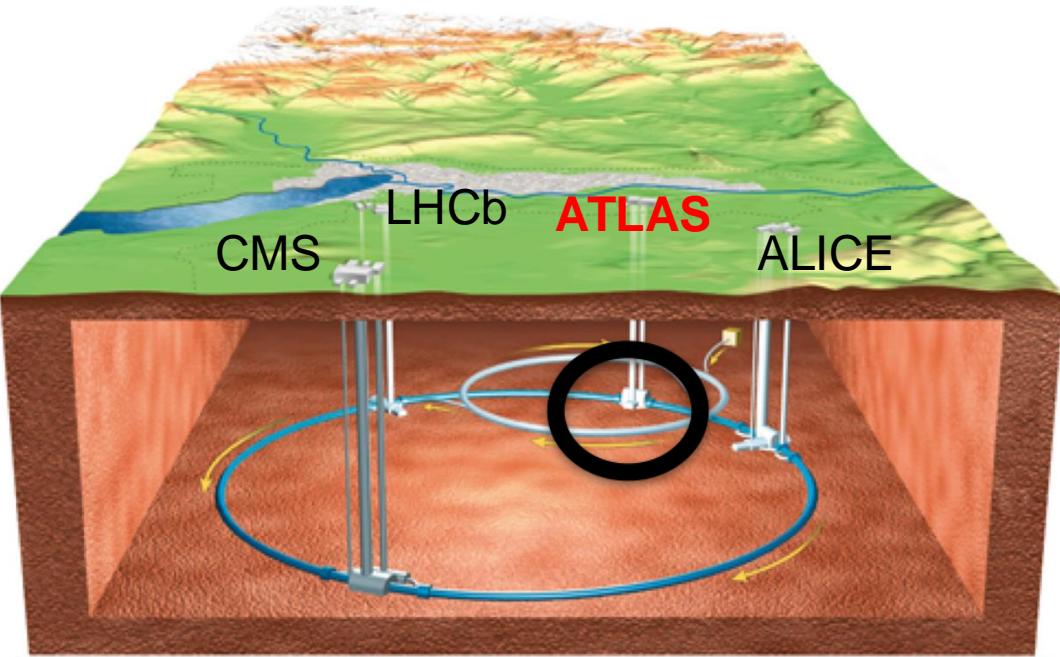
# ITk Upgrade



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## LHC

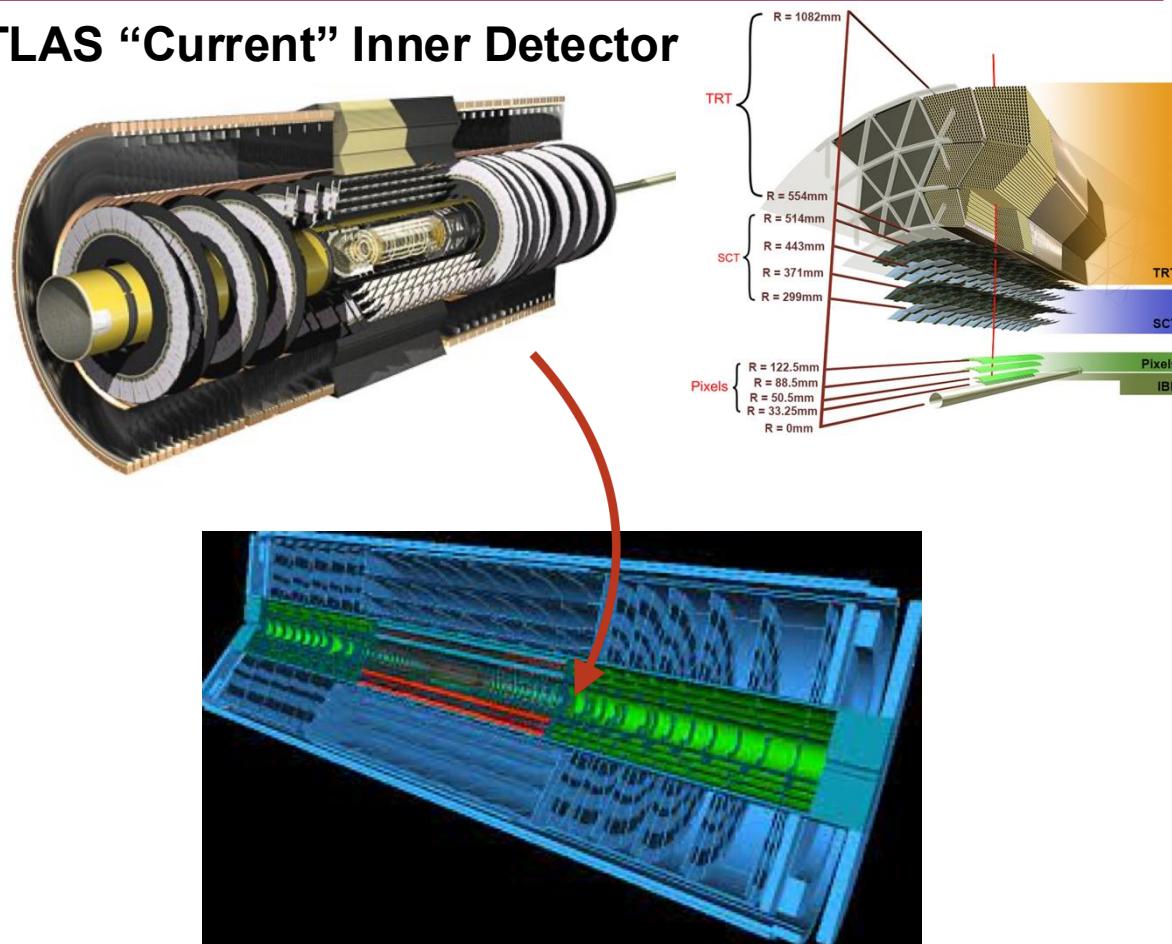
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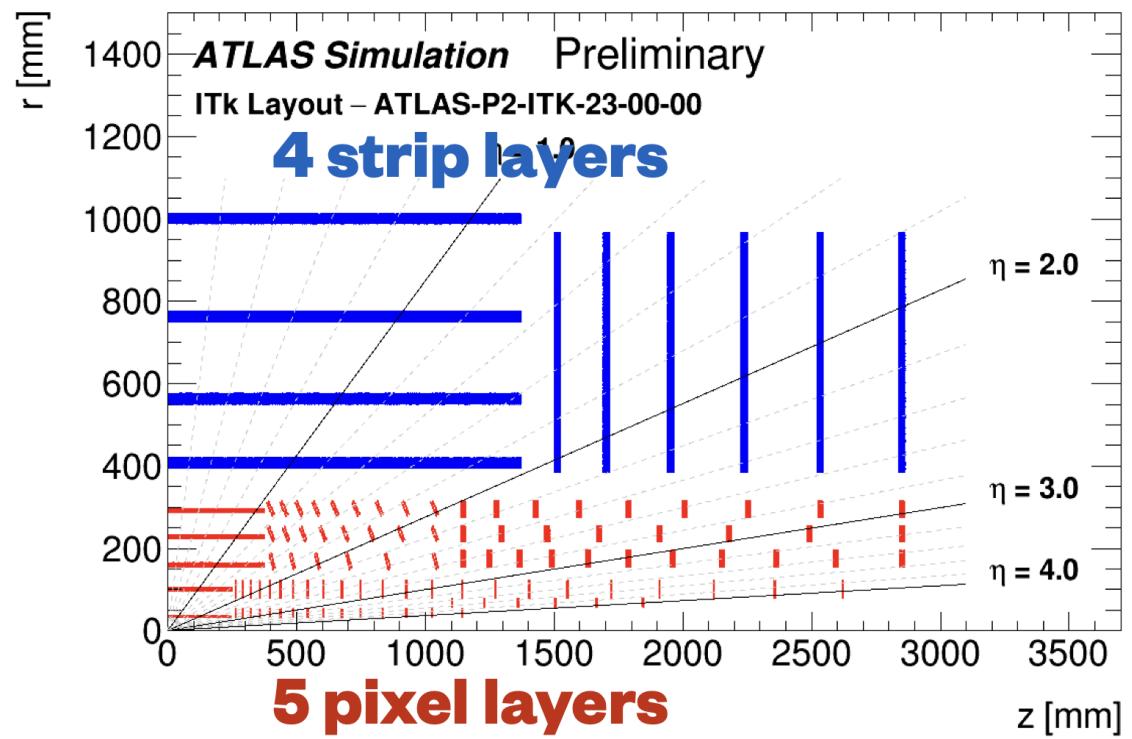
## ATLAS “Current” Inner Detector



The current Inner Detector will be replaced [SEP] by an all silicon Inner Tracker

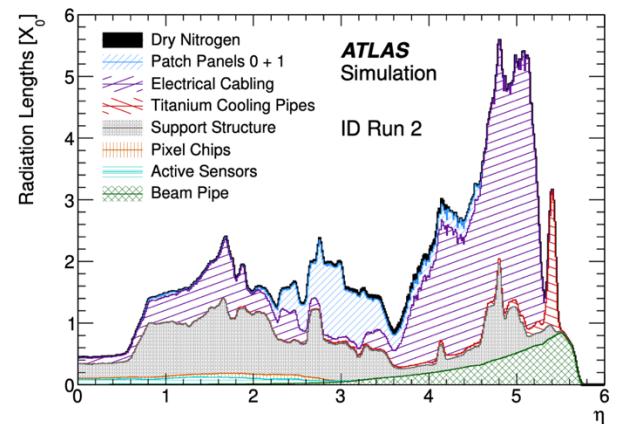
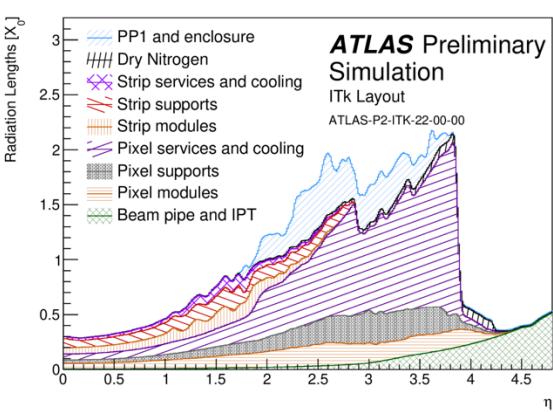
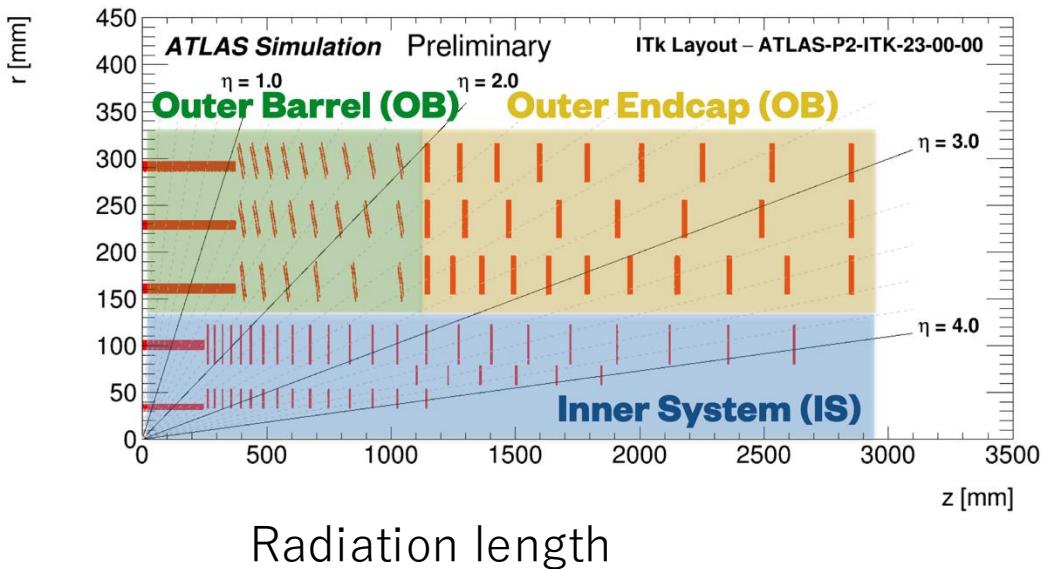
# ITk Layout

- New Inner detector must cope with the HL-LHC environment
  - Better radiation tolerance
    - Fluence of  $2 \times 10^{16} n_{\text{eq}}/\text{cm}^2$ ,  $4000 \text{ fb}^{-1}$
  - Faster readout
    - 5 Gbit/s per data link
  - Finer granularity
    - keep  $\sim 1\%$  occupancy

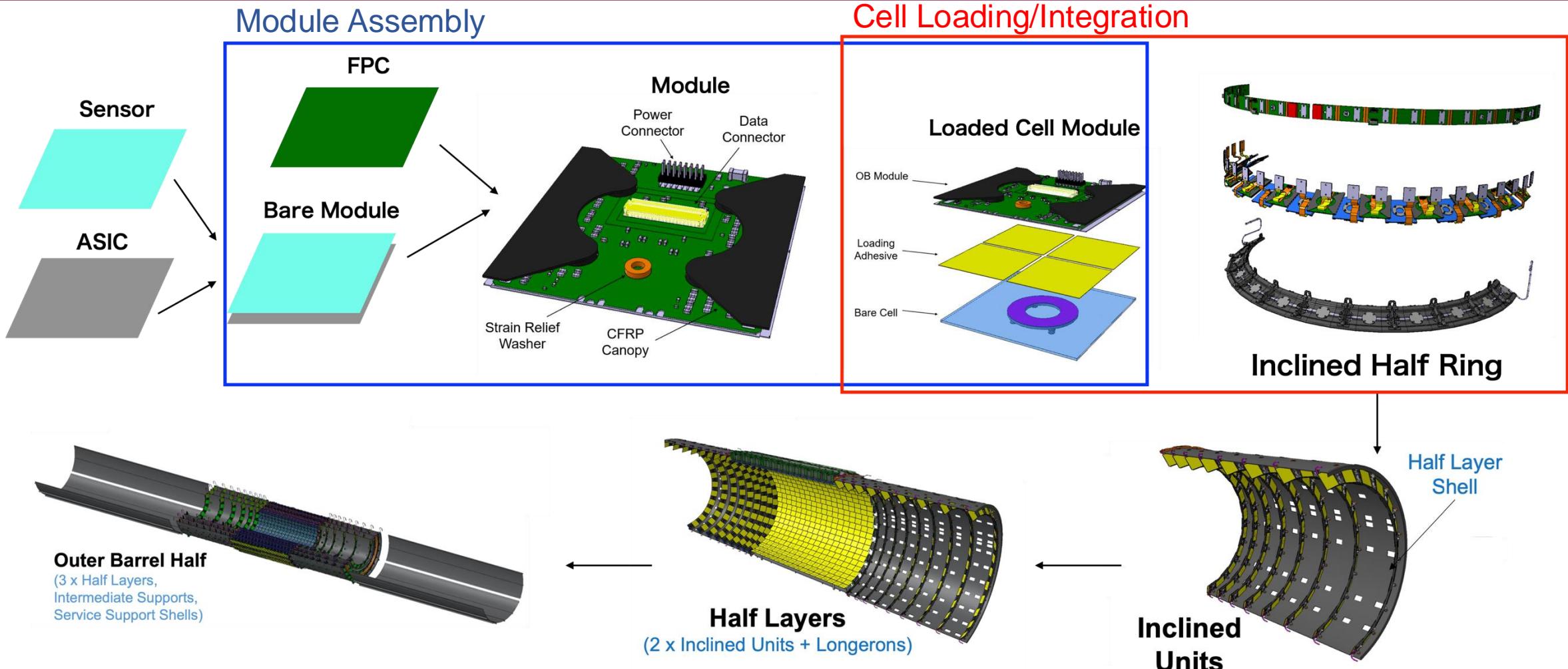


# ITk Key Concepts

- Inner 2 layers are replaceable
- Inclined modules
  - Minimise material and maximise acceptance
- Larger covered area:  $13 \text{ m}^2$ ,  $|\eta| < 4$ 
  - Consists of ~ 10000 modules
- Low material budget
- Serial powering
- Common front-end chip for all layers
- 3D and planar sensors



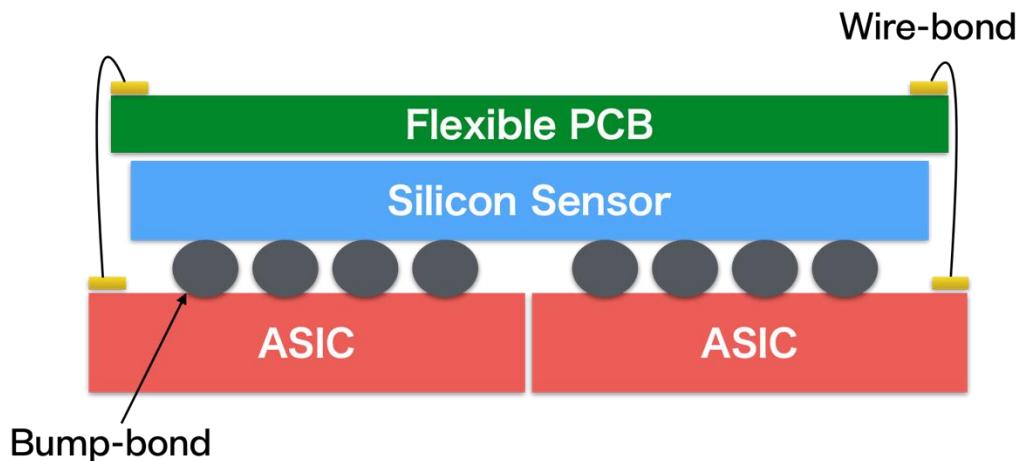
# ITk Production Flow



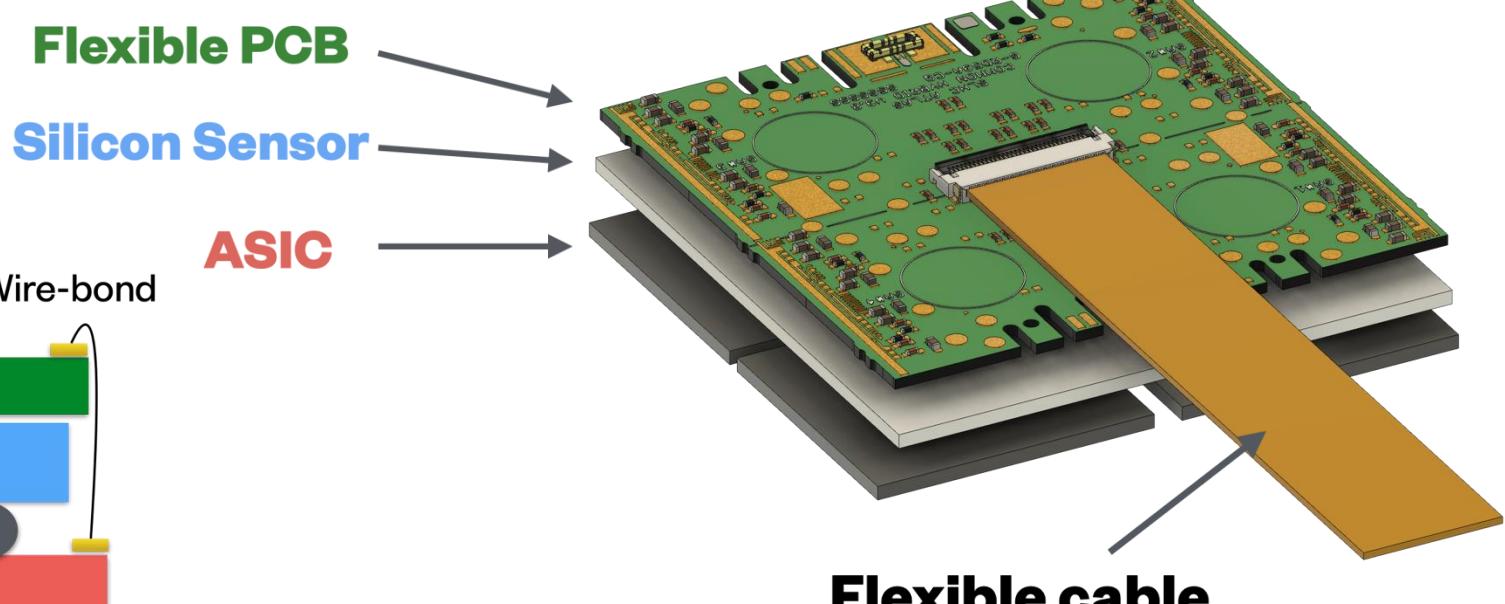
# ITk Pixel Module

## Hybridization

- Fine-pitch bump-bonding
- Bump deposition, UBM, flip chip



Quad module (40 x 40 mm<sup>2</sup>)



2,200 (+ 600) modules (1/4 of total amounts) produced in Japan

50 x 50 µm<sup>2</sup> pixel  
1.28 Gb/s per lane

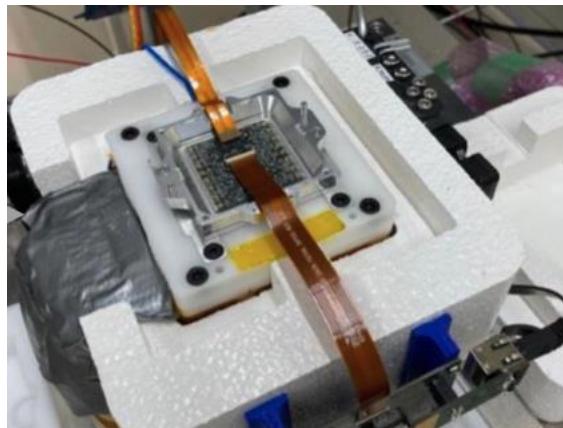
# ITk Activity in Japan

## Module Production

- 3 on-site shifter @ Tateyama
- 5 remote shifter @ anywhere

## KU @ Fukuoka

- satellite site
- developing the system



## KEK @ Tsukuba

- testing site of bare-modules



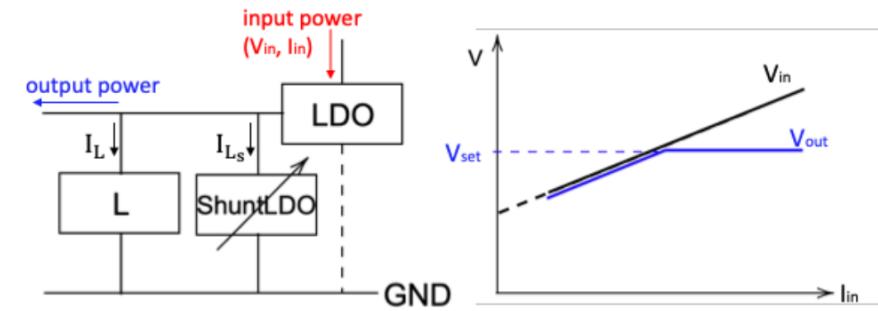
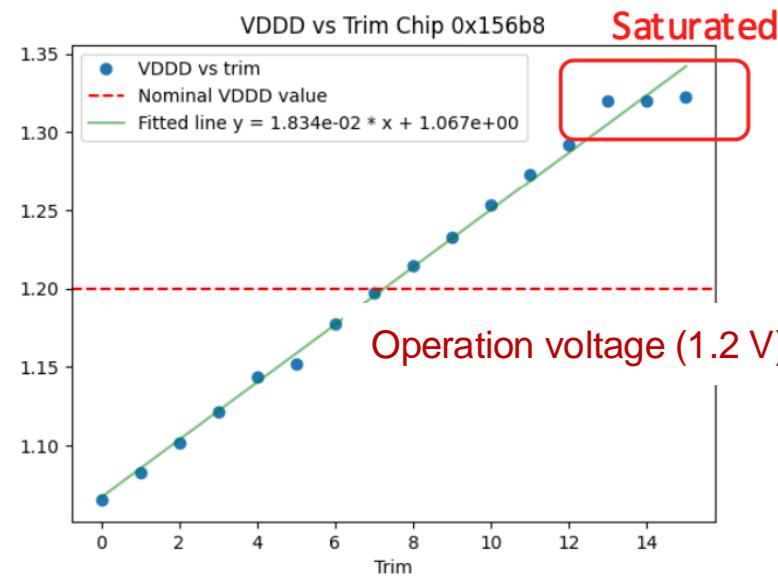
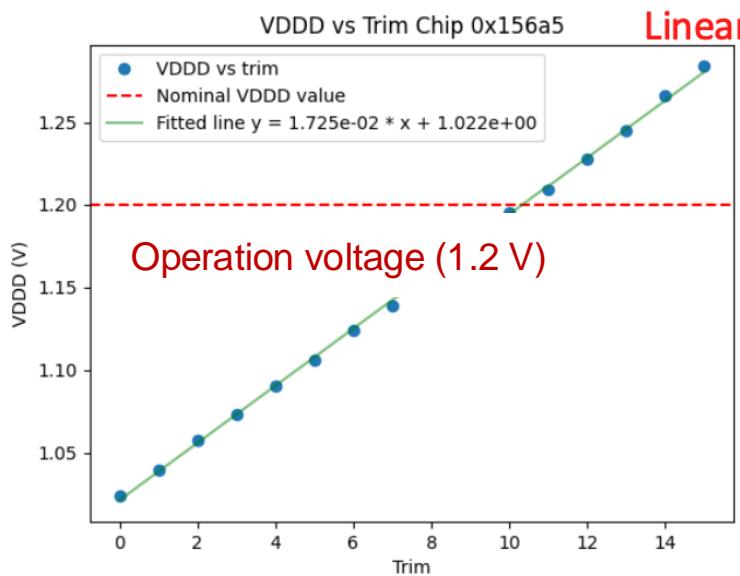
## REPIC @ Tateyama

- Production and testing site of modules



# Module Testing

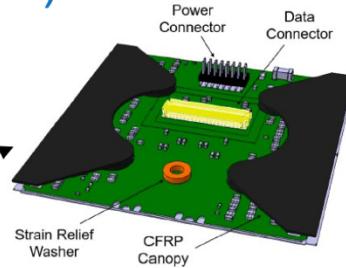
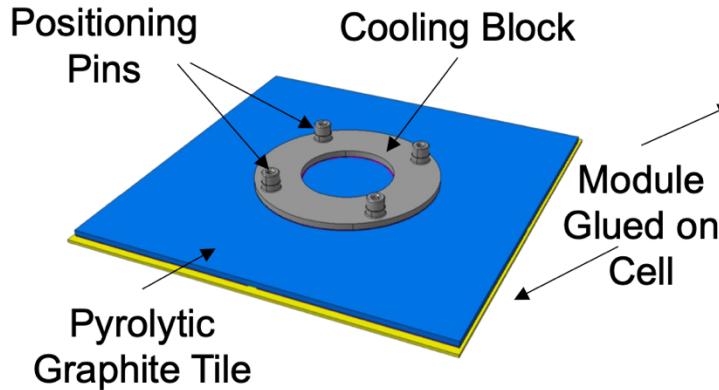
- “Pre”-Production
  - 140 modules have been produced in Japan
  - demonstrate and evaluate production and testing procedure



# Cell Loading / Integration

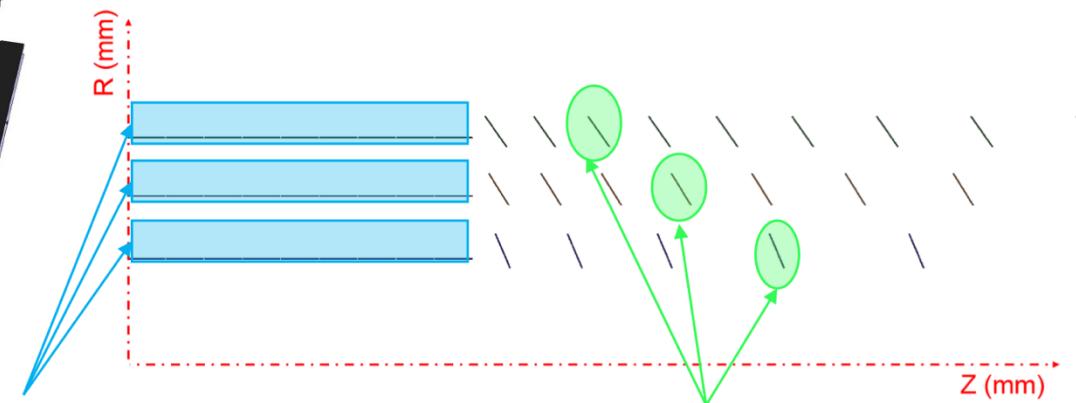
## Module Cells

(Module + PG tile + Cooling Block)

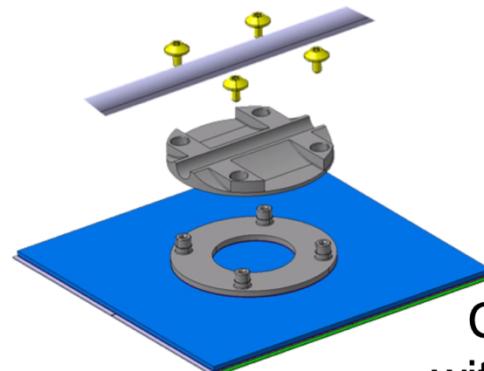


## Functional Local Supports

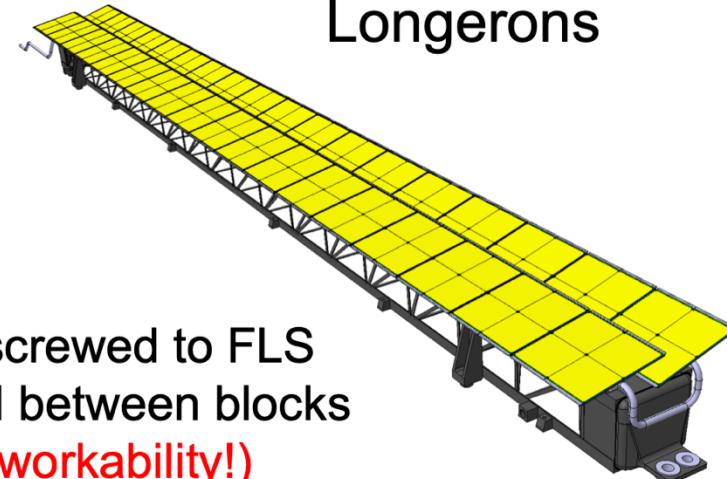
(Base Blocks + Cooling Pipe + CFRP Support Structure)



Longerons



Cells screwed to FLS  
with TIM between blocks  
**(re-workability!)**

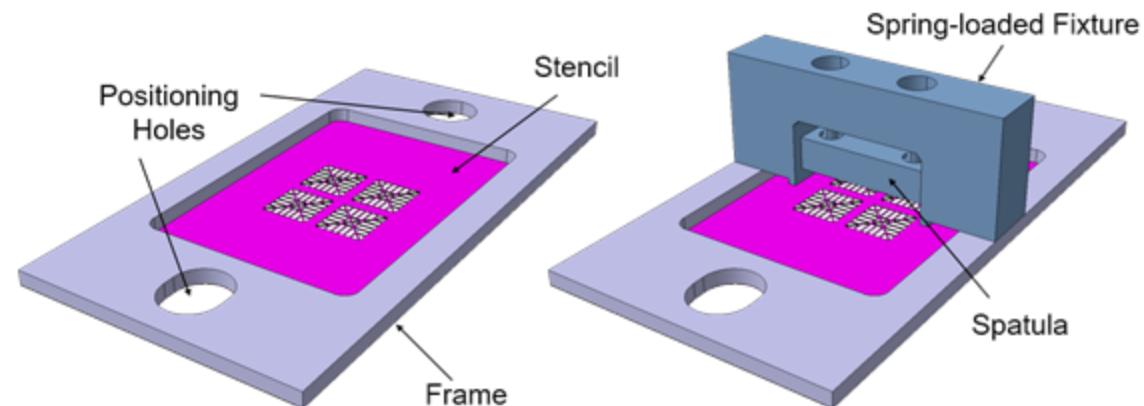
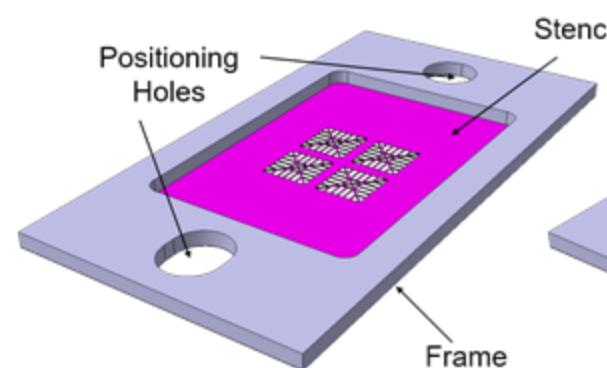
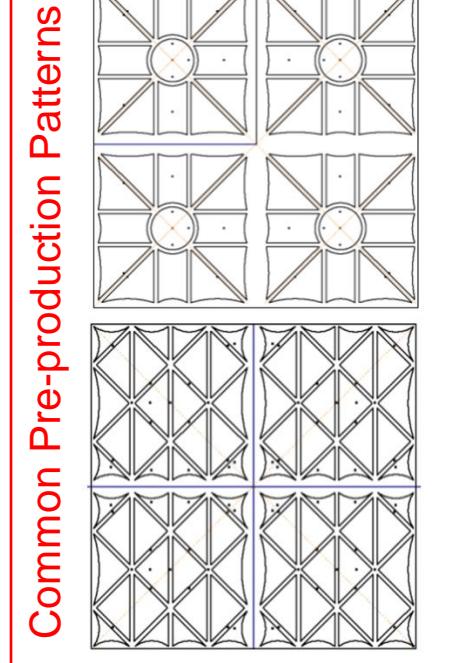
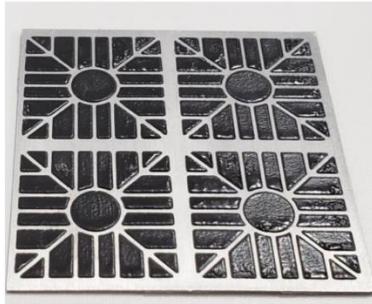
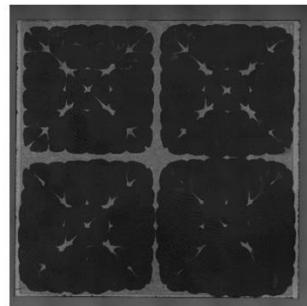
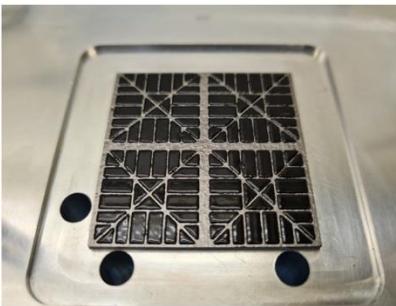


# Cell Loading



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- Stainless-steel stencil with water-jet/laser cut pattern (150 $\mu\text{m}$ -thick)
- Fast, simple and reliable ([developed @ UniGe & Japan for loading Methods I & III](#))
- Pattern combines circular/triangular/rectangular glue areas with escape paths for air trapped below each FE chip → Curved edges added for preproduction

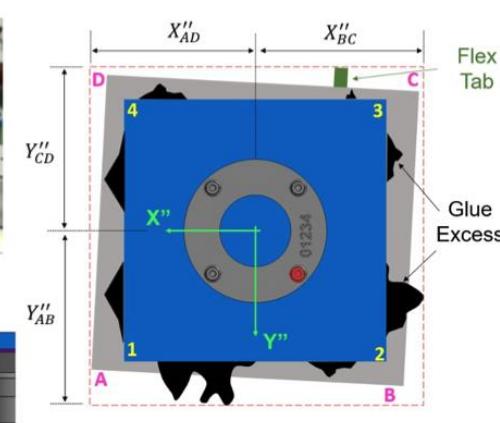
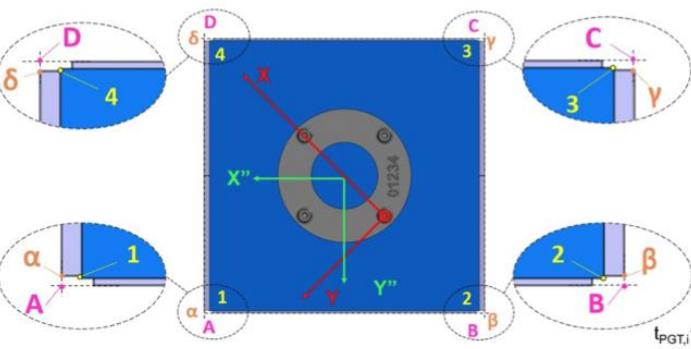
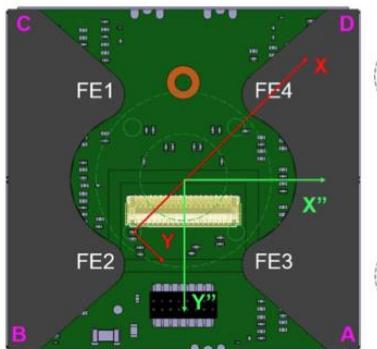


# Loaded Cell Metrology



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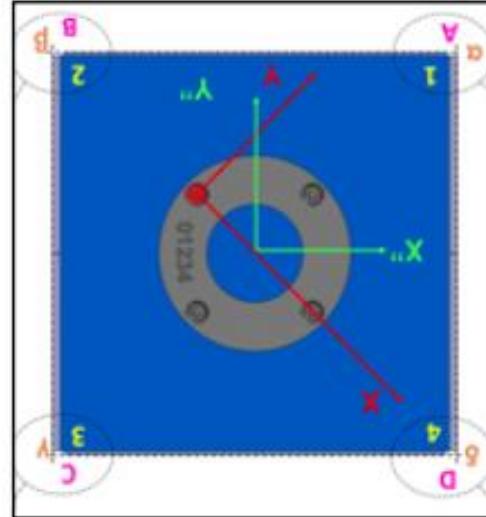
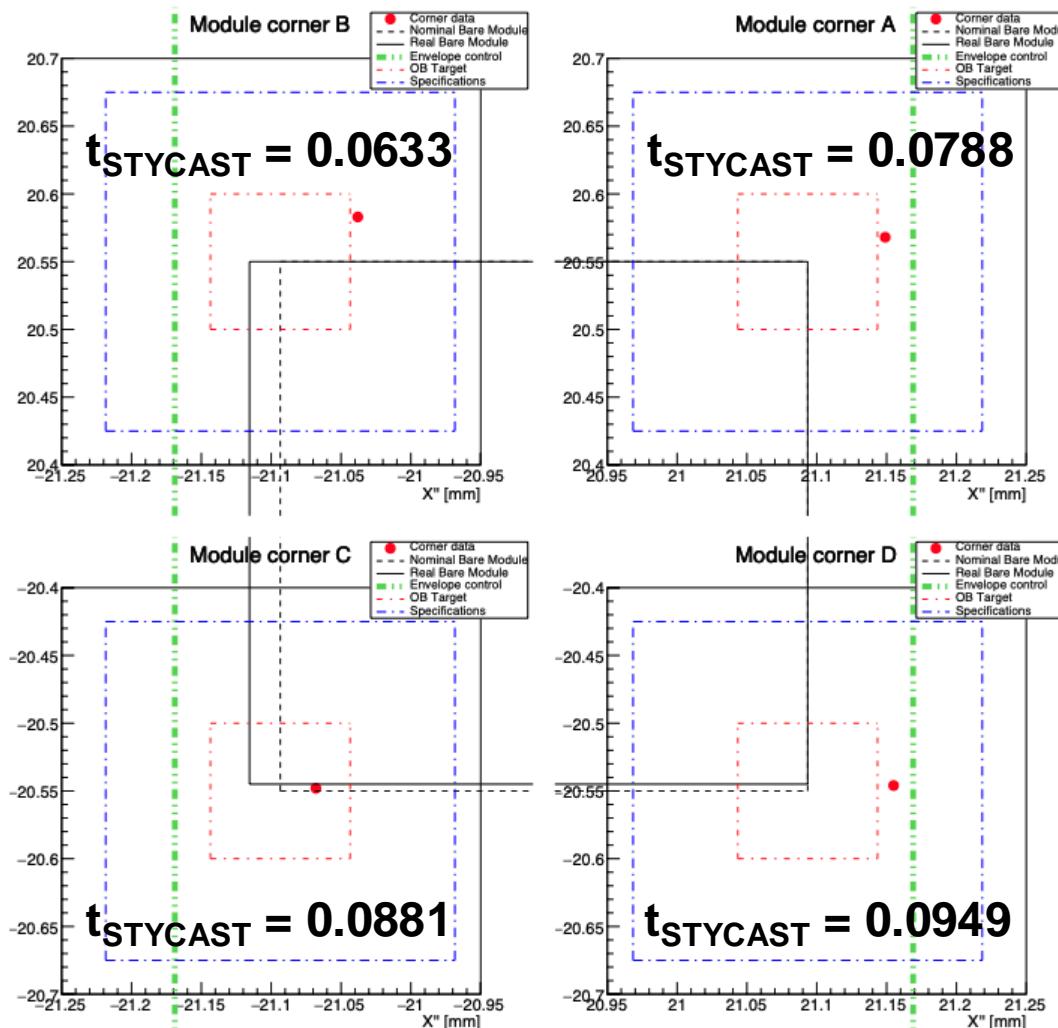
- Optical metrology survey of the backside of the loaded Module Cell
  1. Loading accuracy
  2. Envelope control
  3. Estimated glue thickness



| Results of Metrology Survey of Module Cell |         |  |         |  |  |  |
|--|---------|--|---------|--|--|--|
| Module Corner                              | FE Chip | Measured Coordinates of the Module Corners |         | Measured Coordinate of FE Chip Corners | Estimated Glue Thickness at Module Corners |  |
|  |         | X''  | Y''     |  | $t_{STYCAST}$                              |  |
| A  | FE3     | $X_A''$                                    | $Y_A''$ | $Z_\alpha''$                           | $ Z_\alpha''  - t_{CB+CellGlue+PGT,1}$     |  |
| B  | FE2     | $X_B''$                                    | $Y_B''$ | $Z_\beta''$                            | $ Z_\beta''  - t_{CB+CellGlue+PGT,2}$      |  |
| C  | FE1     | $X_C''$                                    | $Y_C''$ | $Z_\gamma''$                           | $ Z_\gamma''  - t_{CB+CellGlue+PGT,3}$     |  |
| D  | FE4     | $X_D''$                                    | $Y_D''$ | $Z_\delta''$                           | $ Z_\delta''  - t_{CB+CellGlue+PGT,4}$     |  |

## Metrology results stored in ITk PDB

- Assess compatibility with longeron integration  
(Position in Y''-axis critical:  $Y_A''$ ,  $Y_B''$ ,  $Y_C''$ ,  $Y_D''$ ,  $Y_{CD}''$ ,  $Y_{AB}''$ )
- Identify fluctuations across sites/operators



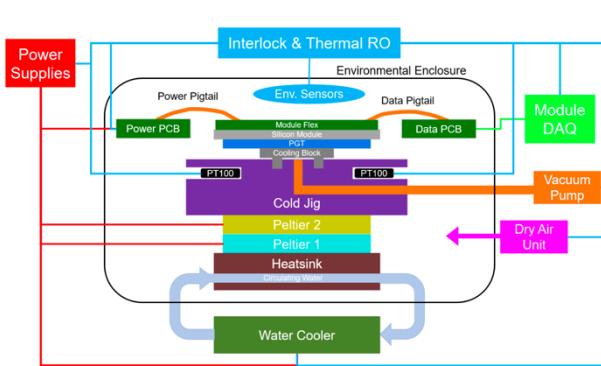
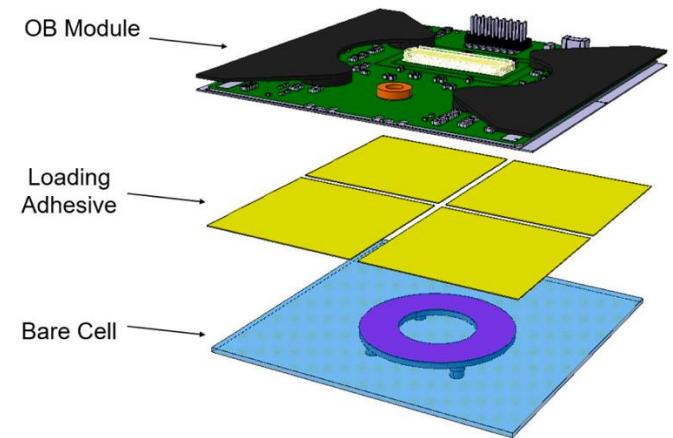
**Red dots:** measured corners  
**Black dotted line:** bare module design size  
**Red dotted line:** OB target ( $\pm 50 \mu\text{m}$ )  
**Blue dotted line:** Specifications ( $\pm 125 \mu\text{m}$ )  
**Green dotted line:** Envelope  
 Horizontal: X" axis  
 Vertical: Y" axis

- Module Thickness
  - A: 0.6998
  - B: 0.7003
  - C: 0.7091
  - D: 0.7089

- Cell Thickness
  - A: 0.621
  - B: 0.637
  - C: 0.621
  - D: 0.614

# Loaded Cell QC

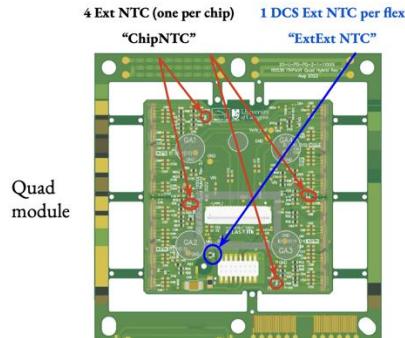
- OB “modules” will be shipped to cell loading site for cell loading
  - at cell loading stage, cooling cell will be attached to the module
  - the performance of the module including the thermal conductivity will be evaluated with common cell qc box
  - measure temperature sensors on the module
  - check correlation with power consumption of FEs



# Thermal Measurement

- To evaluate thermal conductivity, we would like to measure
  - temperature sensors on the module
    - 5 NTCs
    - 3 MOS sensors on each chip
  - cooling head temperature
  - applied voltage to FEs
- most of them can be readout via vmux
  - via vmux
    - 4 NTCs, MOS sensor, VDDA/D, VINA/D
    - already exist in AR and SLDO (VDDA/D, VINA/D)
  - via influxdb (will not be implemented directly)
    - ext. ext. NTC
    - cooling head temperature
    - module power at PSU(?) which can depend on each sites

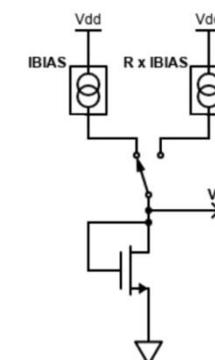
5 NTCs on the FPC



|        |                 |
|--------|-----------------|
| Vmux 2 | NTC_PAD voltage |
| Imux 9 | NTC_PAD current |

$$T = 1/(A + B \ln R + C (\ln R)^3)$$

3 Temp Sens on in the chip

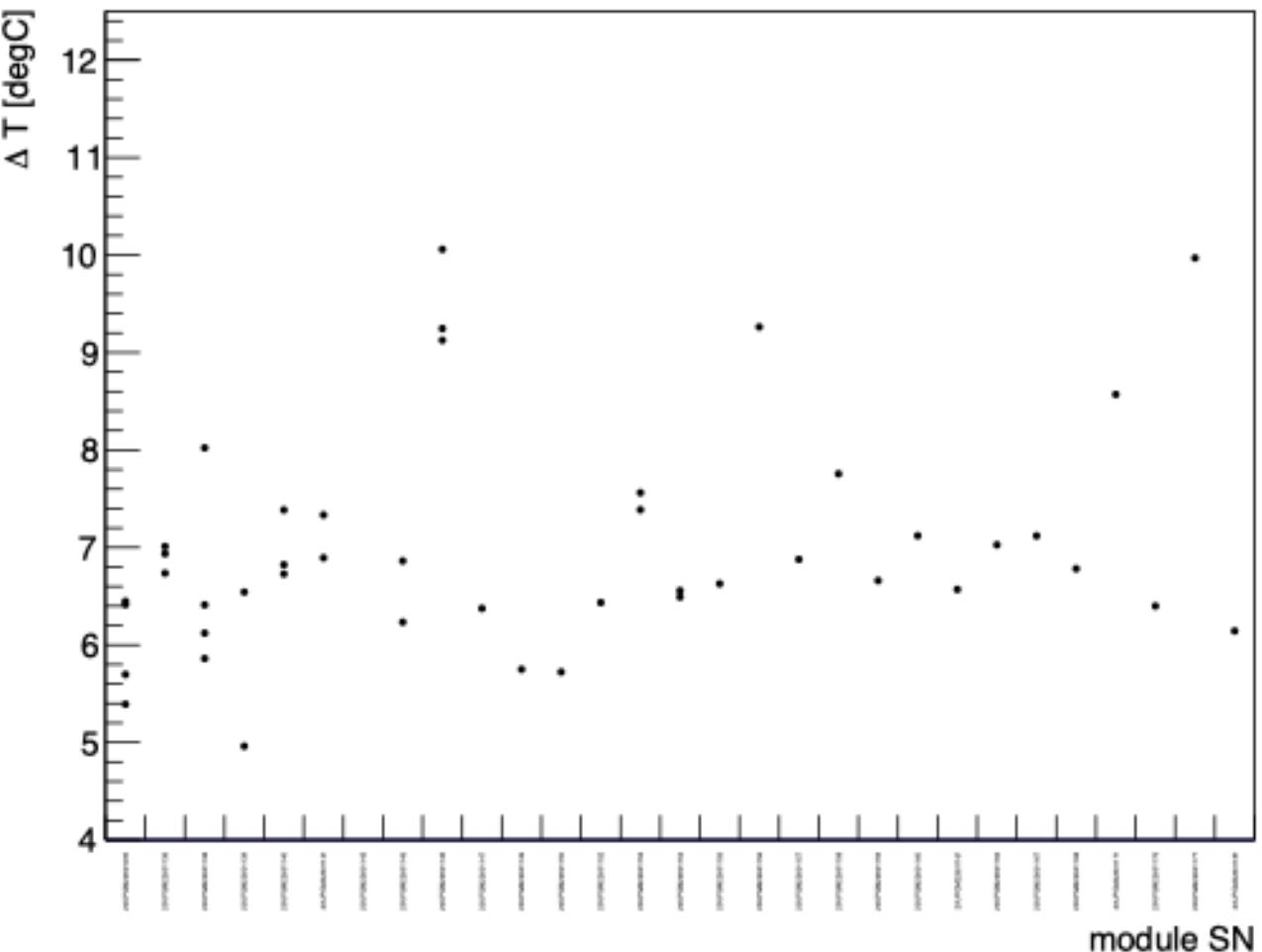


|        |                    |
|--------|--------------------|
| Vmux14 | TEMPSENS Ana. SLDO |
| Vmux16 | TEMPSENS Dig. SLDO |
| Vmux18 | TEMPSENS center    |

$$T = \Delta V_D \times \frac{q}{N_f \times k_B \times \ln(R)}$$

# Results @ KEK

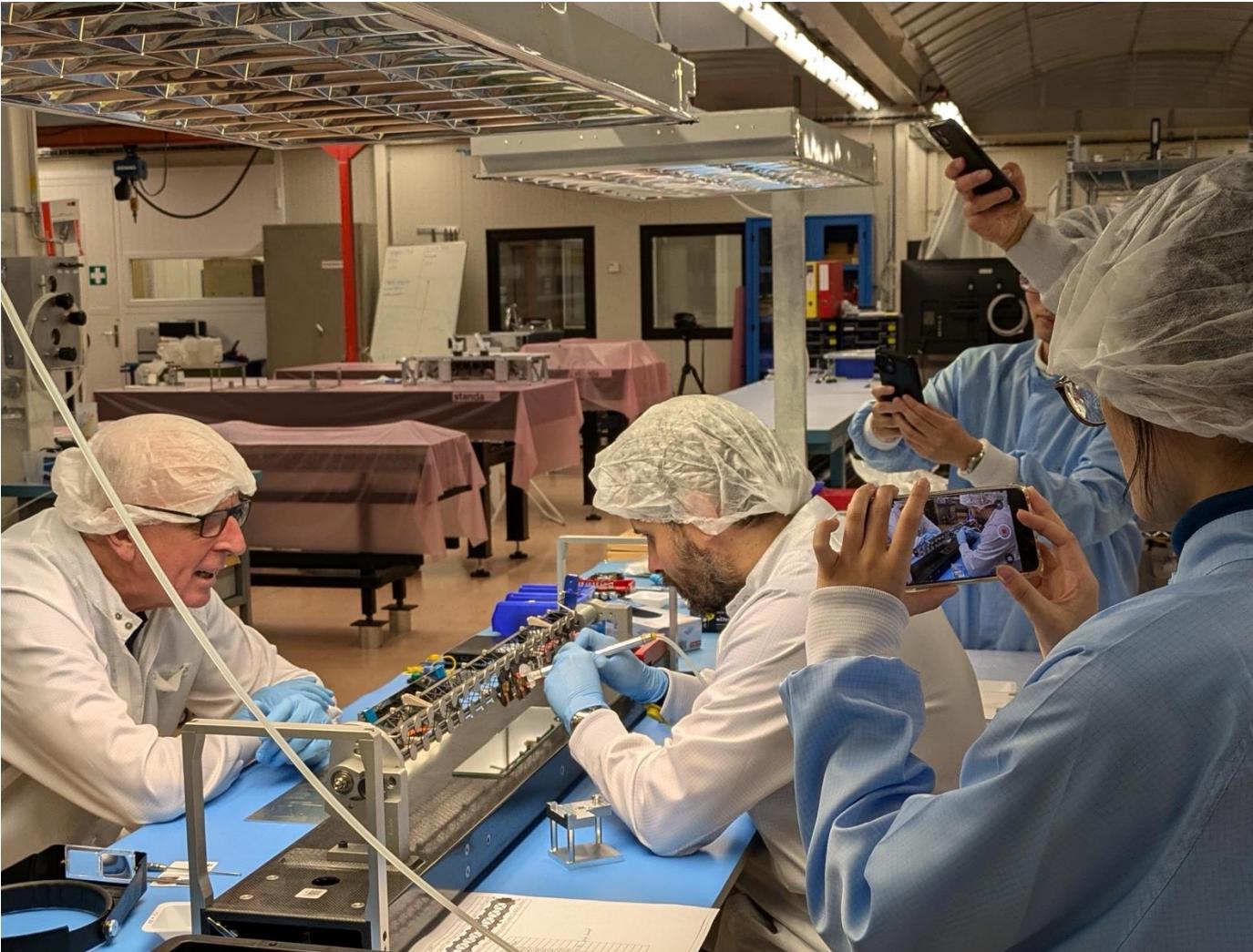
- $\Delta T$  ( $T_{\text{module NTC}} - T_{\text{cooling head}}$ )
  - testing at warm (20 degC)
    - showing only
  - for chip1
  - almost all chips distributed around 6 - 7 degC
  - repeatability: at most  $\pm 1$  degC



# First Integration!!



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# Summary

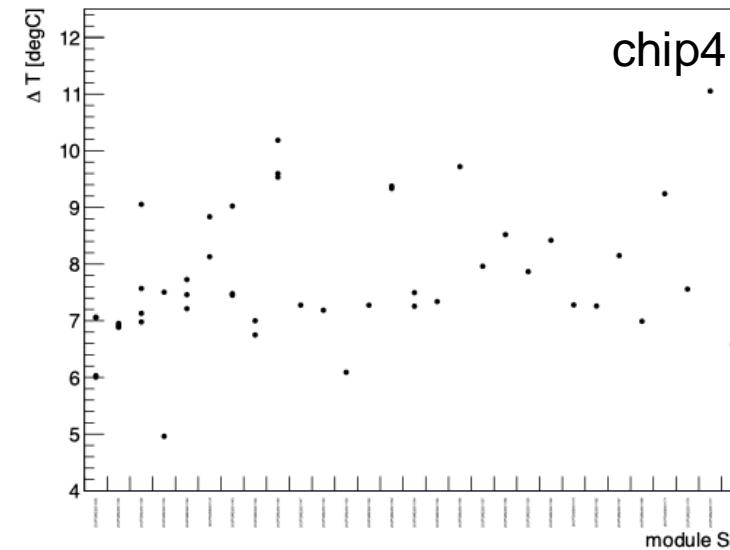
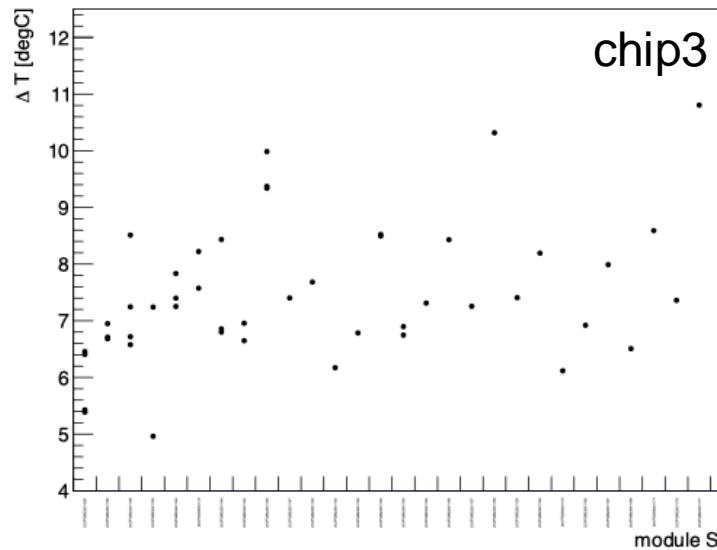
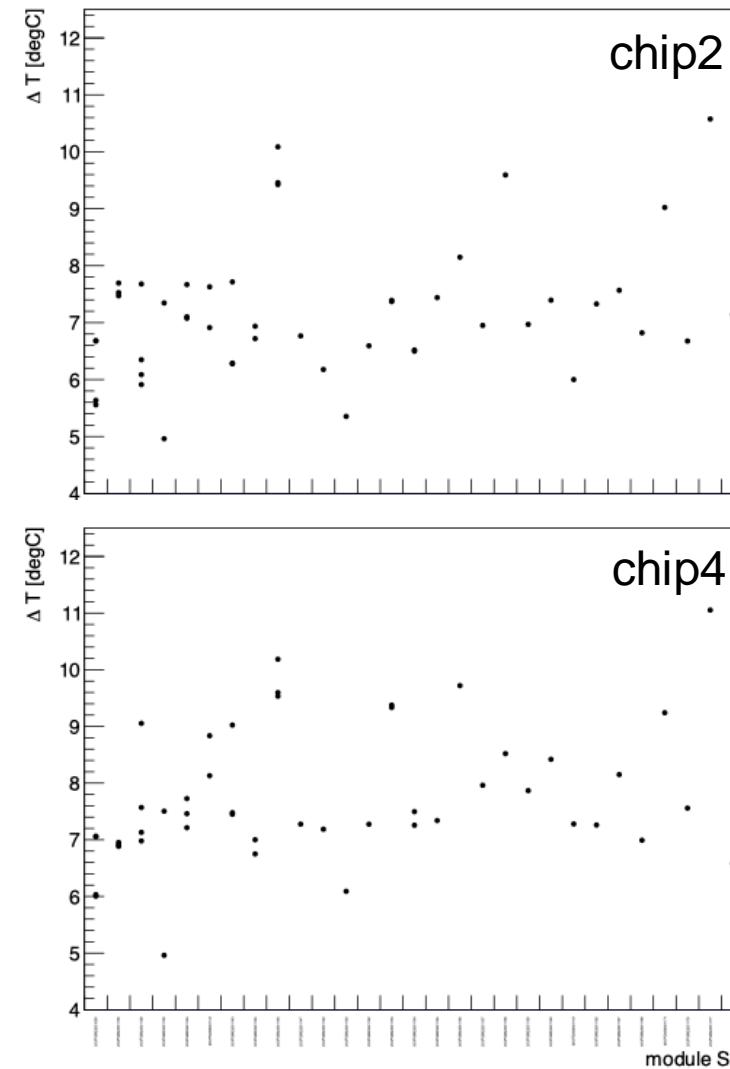
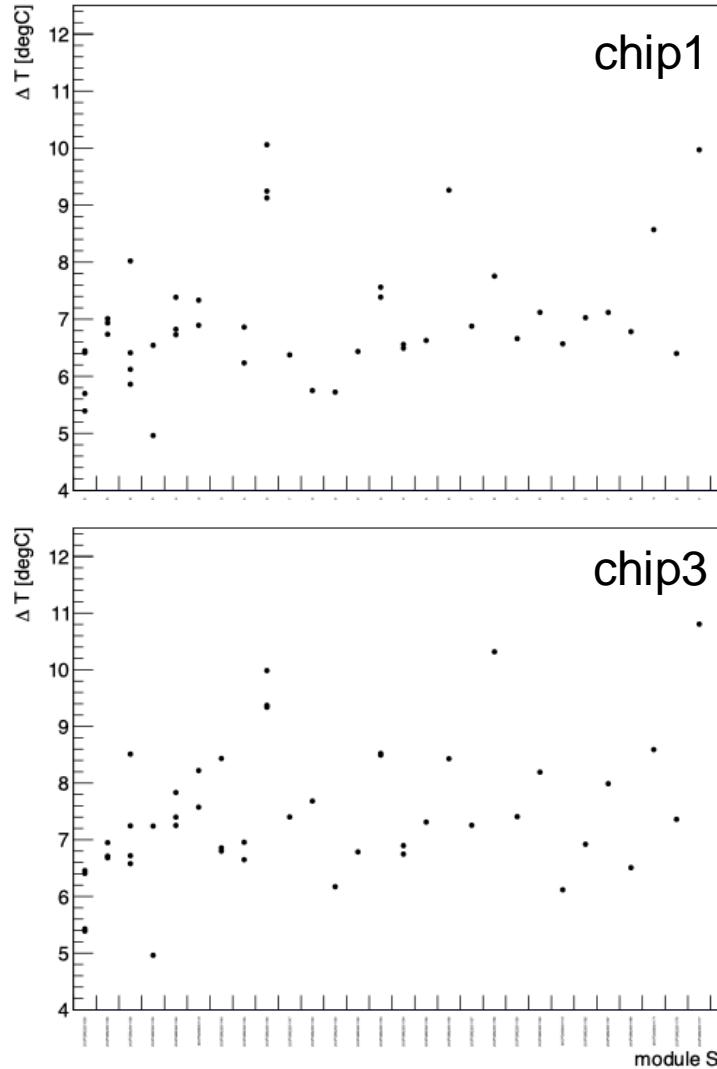
- KU keep contributing to the ATLAS ID (SCT) Operation
- HL-LHC
  - for further physics research
- ITk Upgrade
  - 140 prototype modules have been produced as pre-production
    - many updates for the system has been done and scheduled
  - Mass production have been started
  - KU contributed to module assembling / cell loading, module production and testing

# Backup

# Results @ KEK

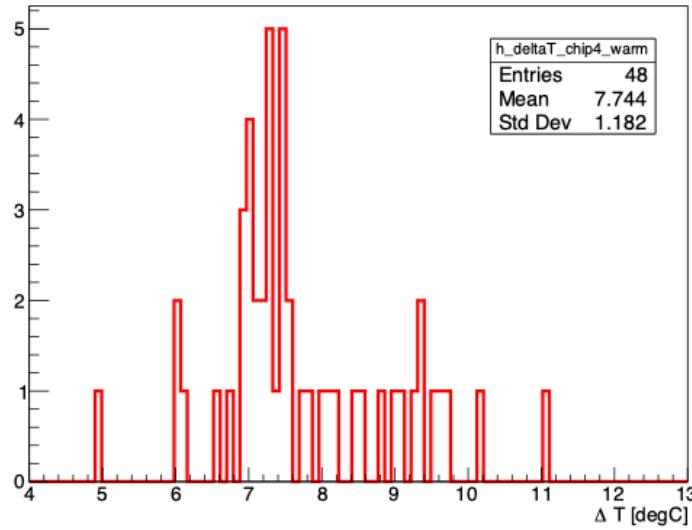
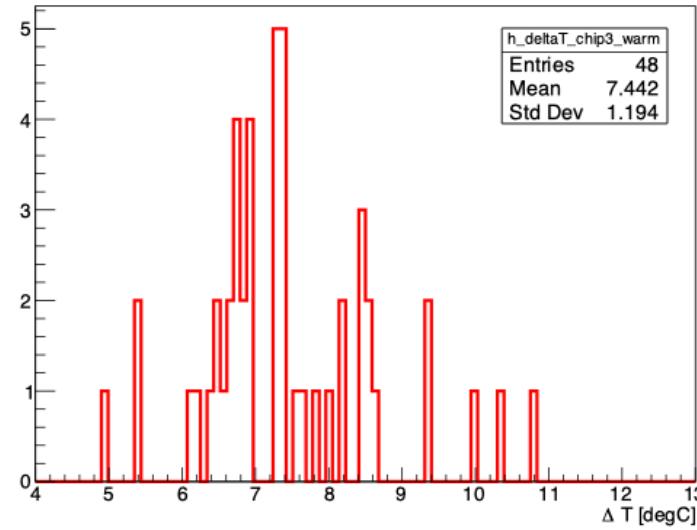
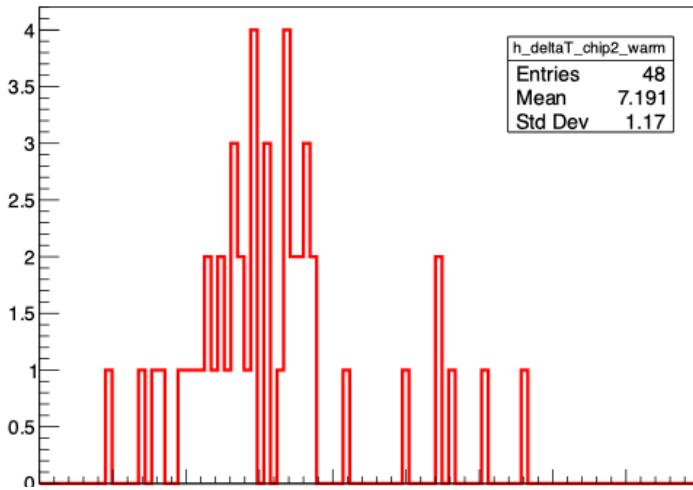
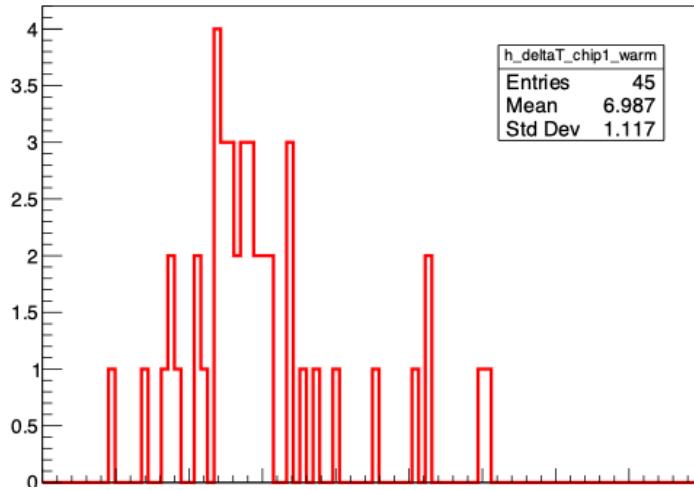


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- $\Delta T$  ( $T_{\text{module NTC}} - T_{\text{cooling head}}$ )
  - testing at warm (20 degC)
    - showing only set temp  $\pm 1$  for ext. NTC
  - chip4 shows higher than others
  - distributed around 7 degC
  - repeatability: at most  $\pm 1$  degC

# Results @ KEK



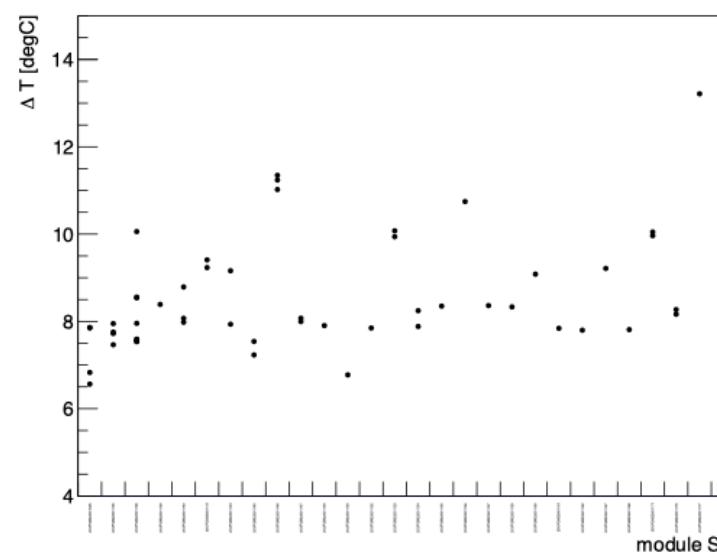
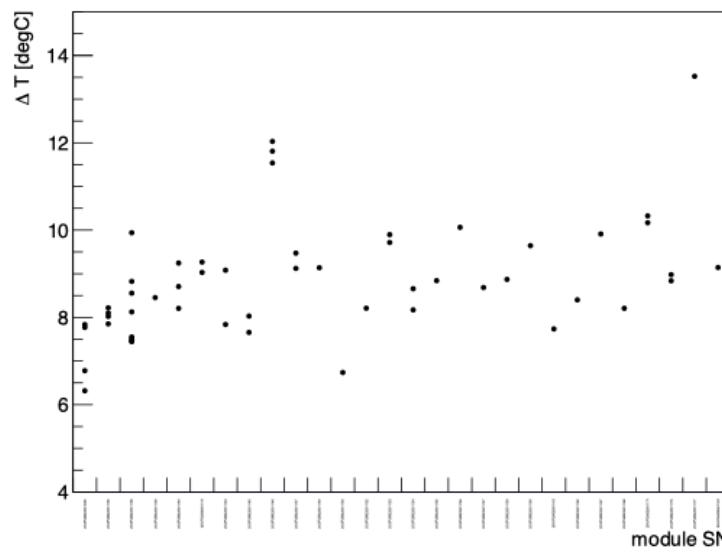
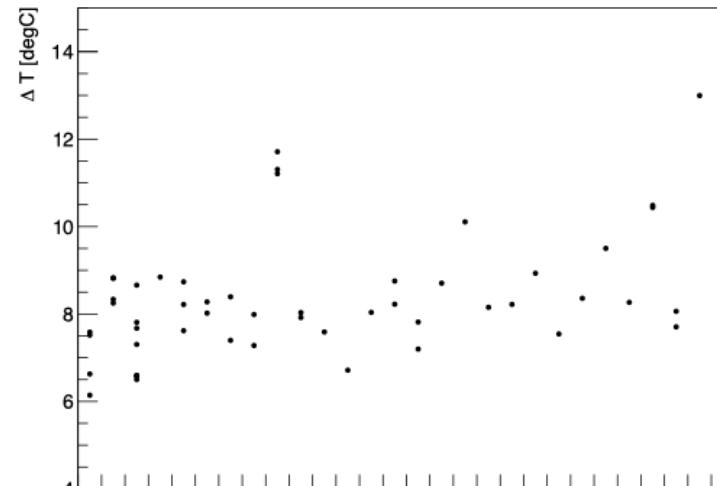
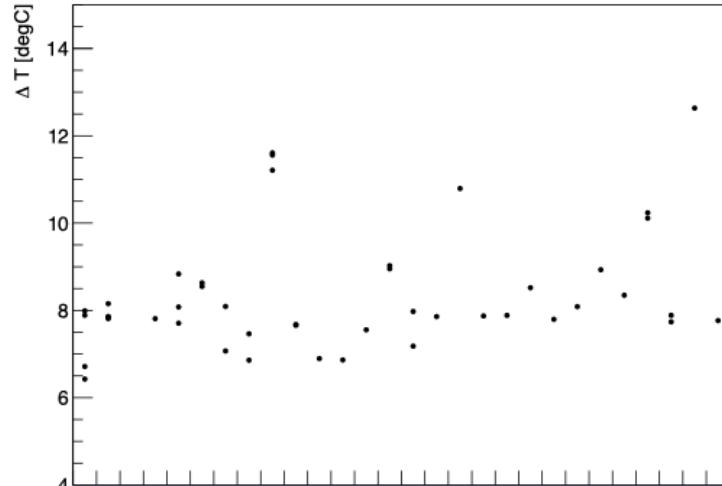
$\Delta T$  ( $T_{\text{module NTC}} - T_{\text{cooling head}}$ )

- testing at warm (20 degC)
  - showing only set temp  $\pm 1$  for ext. NTC
- chip4 shows higher than others
- distributed around 7 degC and there are several module with higher  $\Delta T$

# Results @ KEK



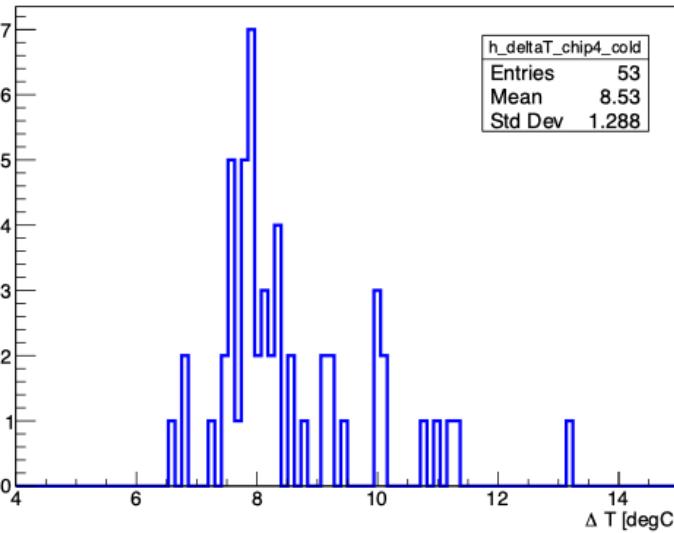
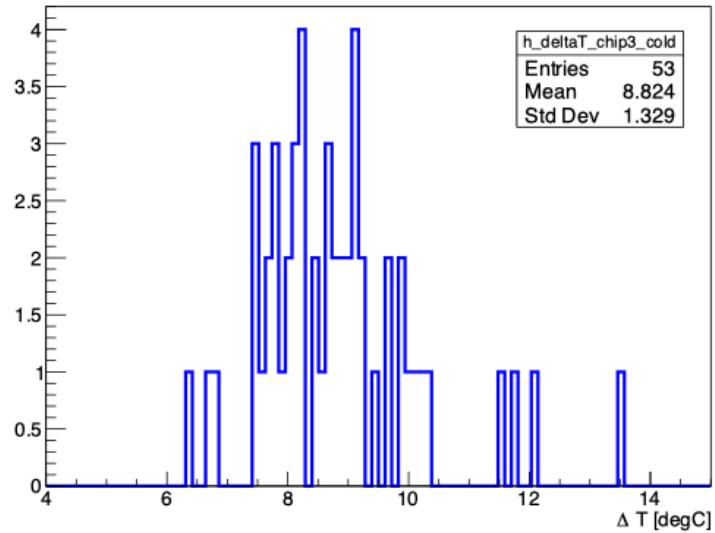
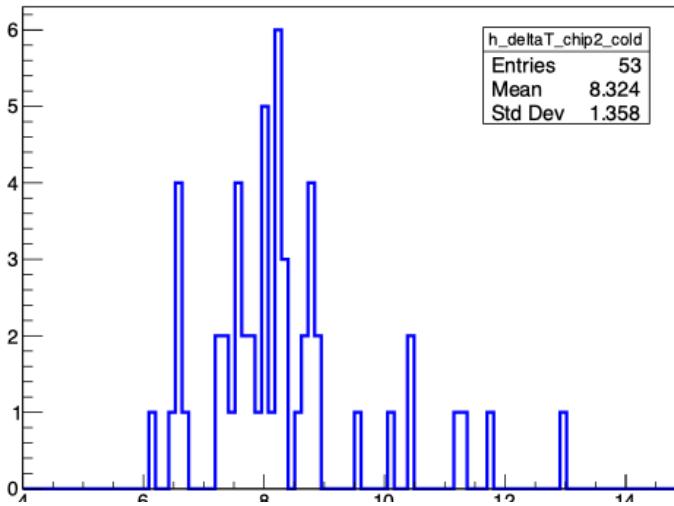
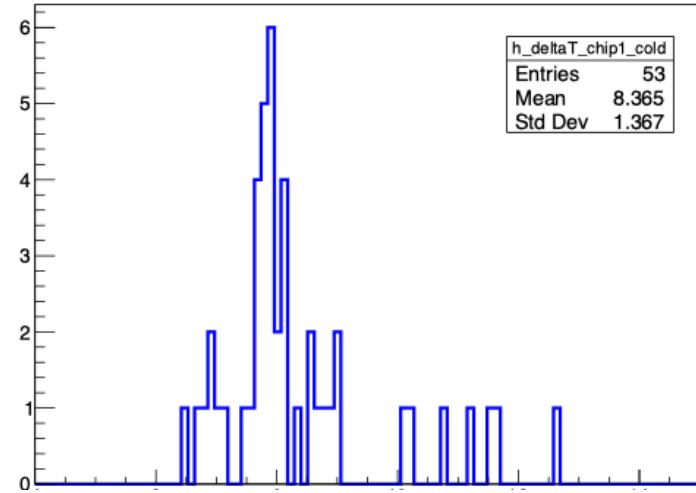
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$\Delta T$  ( $T_{\text{module NTC}} - T_{\text{cooling head}}$ )

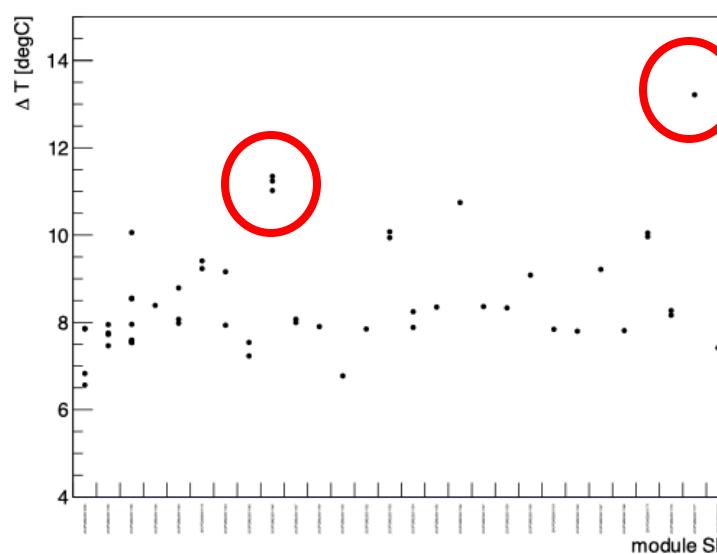
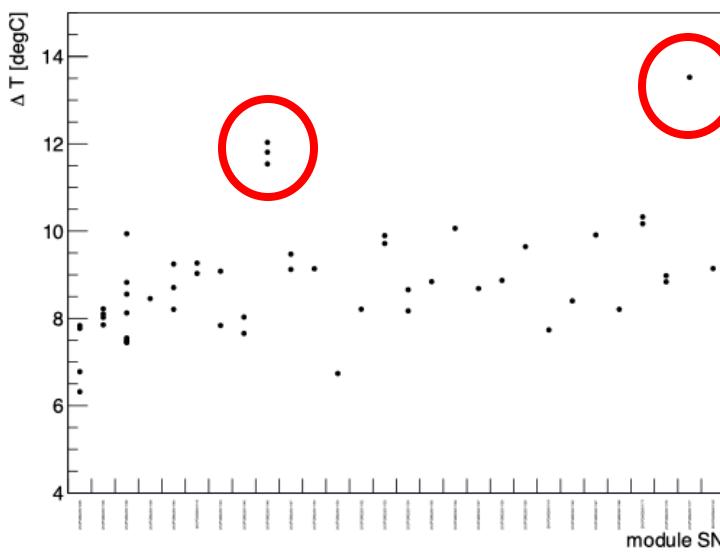
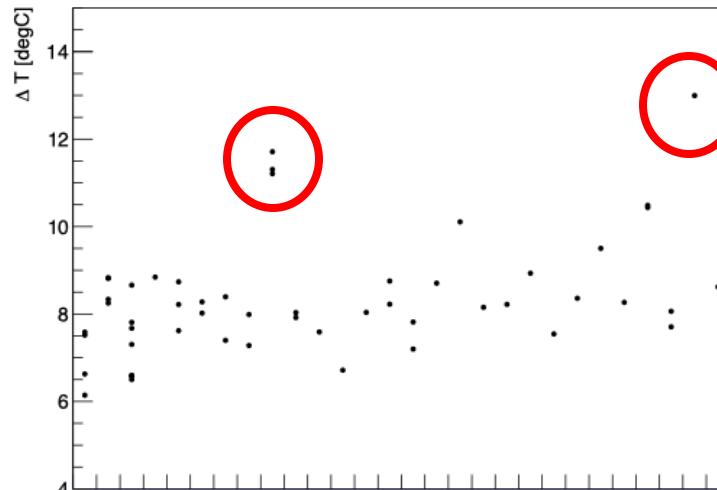
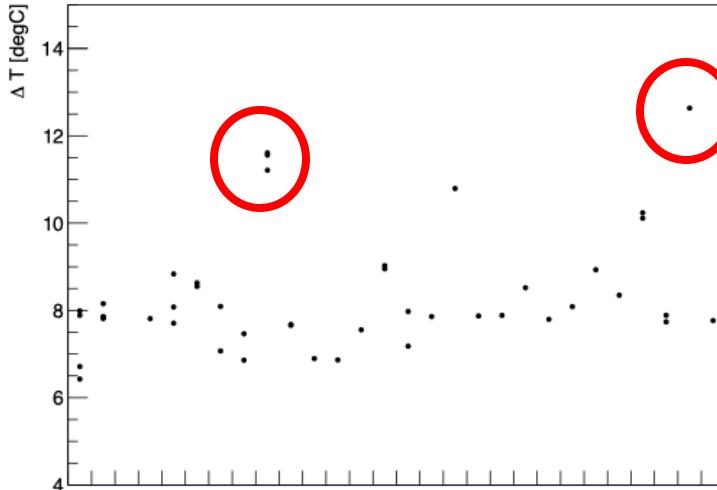
- testing at cold (-15 degC)
  - showing only set temp  $\pm 5$  for ext. NTC
- every chip shows similar distributions
- distributed around 8 degC
- repeatability: at most  $\pm 1$  degC

# Results @ KEK



- $\Delta T$  ( $T_{\text{module NTC}} - T_{\text{cooling head}}$ )
  - testing at cold (-15 degC)
    - showing only set temp  $\pm 5$  for ext. NTC
  - distributed around 8 degC
  - every chip shows similar distributions

# Results @ KEK



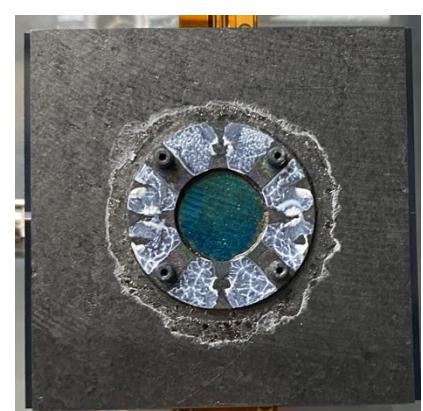
There are two relatively worse thermal conductivity modules

- The cell of them looks different from others

“normal” cell



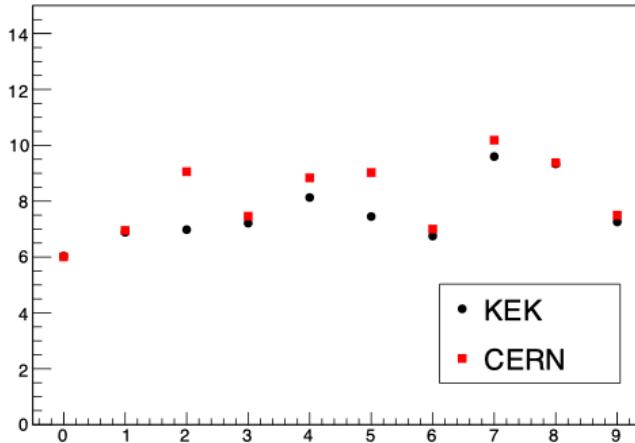
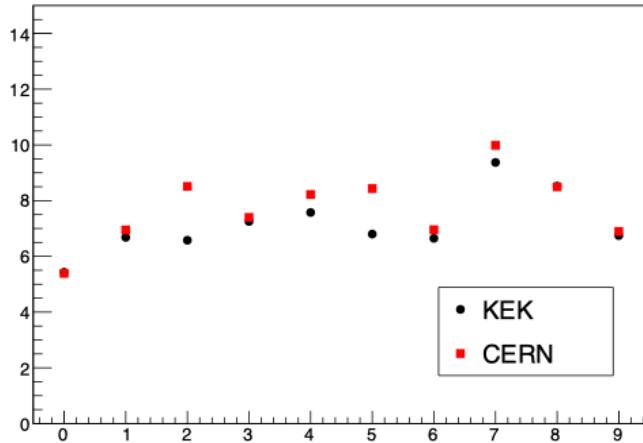
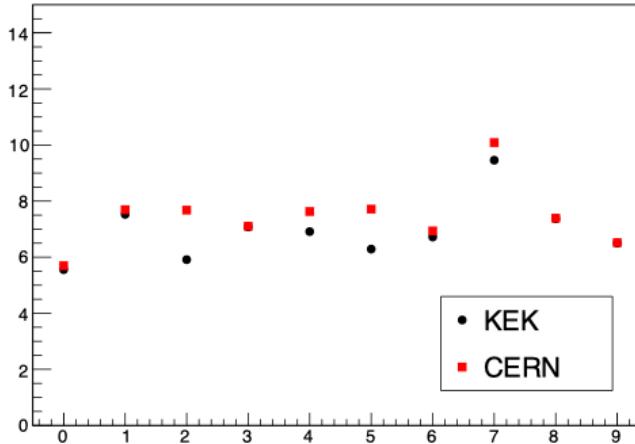
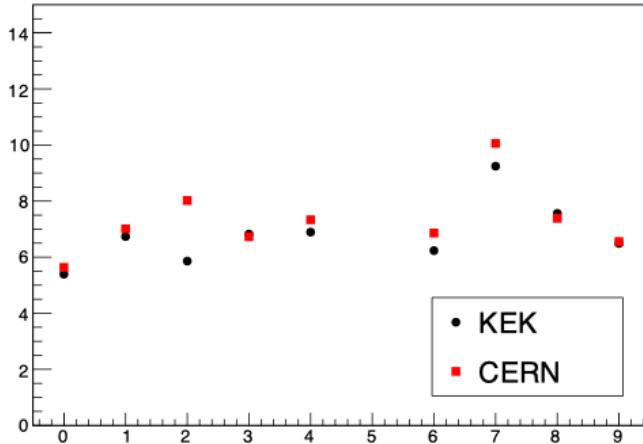
“bad” cell



# Comparison of tests @ CERN



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# Loaded Cell Metrology 3

- Optical metrology survey of the backside of the loaded Module Cell

1. Loading accuracy
2. Envelope control
3. Estimated glue thickness

KEYENCE VR-6000



1mm x 1mm



- Measured by two steps

1. Cell measurement at KEK
  - will be included in KEK Fuji shift
  - need to consider how to handle data
2. Loaded cell measurement at REPIC
  - will be included in REPIC shift
  - already implemented, in terms of the measurement
  - localDB

